## 1. Introductions

## 1.1. Basic Function and Design Goals

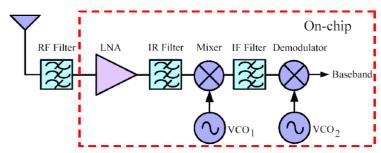


Fig. 1.1 A typical architecture of radio receiver

#### 1.1.1. Basis Function

- > Provide gain to minimize noise contributed by subsequent blocks
- > Contribute as low noise as possible
- > Provide high linearity
- > Provide 50 ohm input impedance
- > Low power dissipation

### 1.1.2. Design Goals

- > Simultaneous Noise and Input Matching
- > Any given amount of power dissipation

## 2. Fundamental of Low Noise Amplifier

## 2.1. Noise Figure and Noise Factor

The most popular basis definition of noise figure is given by Friis

$$NF = 10 \log \left( \frac{SNR_{in}}{SNR_{out}} \right) = 10 \log (F)$$
 (2.1)

where  $SNR_{in}$  and  $SNR_{out}$  are the signal-to-noise ratios measured at the input and output

NF measures how much the SNR degrades as the signal passes through a system
If a system has no noise, then  $SNR_{in} = SNR_{out}$   $\rightarrow$  NF of noiseless system is equal to 0 dB

### 2.2. Power Gain

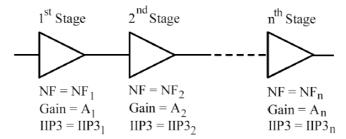


Fig. 2.1 NF of the cascade system

$$NF_{total} = NF_1 + \frac{NF_2 - 1}{A_1} + \dots + \frac{NF_n - 1}{A_1 \cdot A_2 \cdot \dots \cdot A_n}$$
 (2.2)

- NF of overall system is dominated by first stage
- → LNA need to have high gain to suppress the noise contributed by later stages
- However be careful when design high gain because it easily becomes oscillator

### 2.3. Linearity

- ✓ LNA must remain linear even when strong signals are bein g received
- ✓ The nonlinear can be characterized by 1 dB compression point (P-1dB) or input referred third order intercept point (IIP3)
  - P-1dB is defined as the input power at which the output power gain drops by 1 dB
  - IIP3 is defined as the point at which extrapolated fundamental response and the extrapolated third order intermodulation line intersect

$$IIP3 = \frac{P_{out} - P_{out,IM3}}{2} + P_{in} \qquad \frac{A_{P-1dB}}{A_{IIP3}} \approx -9.6 \ dB$$

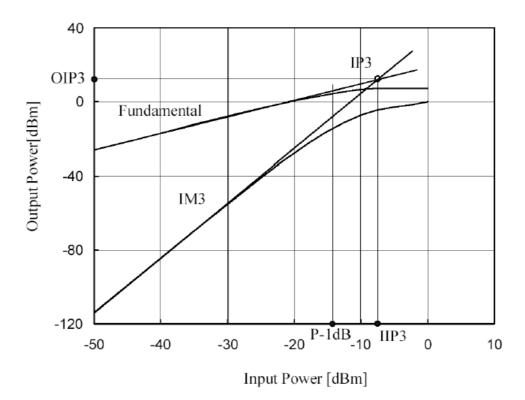


Fig. 2.2 A Plot of IIP3

# 3. Low Noise Amplifier Design Techniques

# 3.1. Classical Noise Optimization Technique

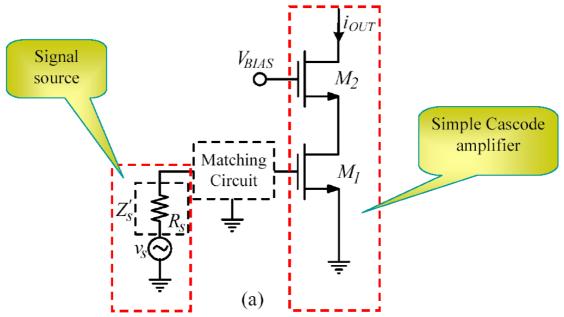
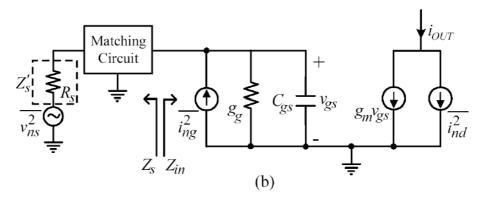


Fig. 3.1. (a) The schematic of cascode topology apply to adopt CNM technique (b) Small signal equivalent circuit



✓ The mean-square channel thermal noise current

$$\overline{i_{nd}^2} = 4kT\gamma g_{d0}\Delta f \tag{3.1}$$

√ The mean-square gate-induced noise current

$$\overline{i_{ng}^2} = 4kT\delta g_g \Delta f \tag{3.2}$$

$$g_g = \frac{\omega^2 C_{gs}^2}{5g_{d0}}$$
 (3.3)  $c = \frac{\overline{i_{ng} \cdot i_{nd}^*}}{\sqrt{\overline{i_{ng}^2} \cdot \sqrt{\overline{i_{nd}^2}}}}$  (3.4)

- $g_{do}$  is drain-source conductance at zero drain-source voltage
- k the Boltzmann constant
- T absolute temperature
- $C_{gs}$  drain-source capacitor
- $\gamma$  has value of 1 at  $V_{DS}$ = 0 and 2/3 at saturation mode
- y increases to more than 2 in short channel device
- $\delta = 4/3$  in long-channel and increases in short-channel devices
- c is correlation coefficient and equal to j0.395

## The noise parameters are given by [3]

✓ Noise Resistance

$$R_n^o = \frac{\gamma}{\alpha} \cdot \frac{1}{g_m} a \tag{3.5}$$

- For small  $R_n \rightarrow$  increase transistor size and drain current
- ✓ Minimum Noise Figure

$$F_{min}^{o} = 1 + \frac{2}{\sqrt{5}} \frac{\omega}{\omega_{T}} \sqrt{\gamma \delta (1 - |c|^{2})}$$
 (3.6)

- Strong function of  $\omega_T$  and  $\omega$
- Technology scaling  $\rightarrow \omega_T \uparrow \gamma$ ,  $\sigma$ , and  $c \downarrow \rightarrow F_{min} \downarrow$

## ✓ Optimum Noise Admittance

$$Y_{opt}^{o} = \alpha \omega C_{gs} \sqrt{\frac{\delta}{5\gamma} (1 - |c|^{2})} - sC_{gs} \left( 1 + \alpha |c| \sqrt{\frac{\delta}{5\gamma}} \right)$$

$$\alpha = g_{m}/g_{do}$$
(3.7)

- Composed of real and imaginary value
- · Increase with Tr. size and frequency
- Imaginary part: inductive but capacitive in frequency behavior
   → allow only narrowband matching

# ✓ From Fig. (b), the input admittance is

$$Y_{in}^{o} = j\omega C_{gs}$$

$$Y_{in}^{o*} = -j\omega C_{gs}$$

$$Y_{opt}^{o} = \alpha\omega C_{gs} \sqrt{\frac{\delta}{5\gamma} (1-|c|^{2})} - sC_{gs} \left(1+\alpha|c|\sqrt{\frac{\delta}{5\gamma}}\right)$$

- $Y_{in}^{o^*}$  Imaginary component only
- Inherent mismatch between  $Y_{in}^{o^*}$  and  $Y_{opt}^o$ 
  - → no simultaneous noise and input matching

- ✓ Design for minimum NF by presenting  $Z_{opt}$  to the given transistor
- **✓** Typically require matching circuit
- ✓ Can achieve NF =  $F_{min}$  of input transistor
- ✓ Inherent mismatch between  $Z_{opt}$  and  ${Z_{in}}^*$  → input mismatch
- **✓** Often compromise gain and noise performance

## 3.2. Simultaneous Noise and Input Matching Technique

### 3.2.1. Circuits Topology

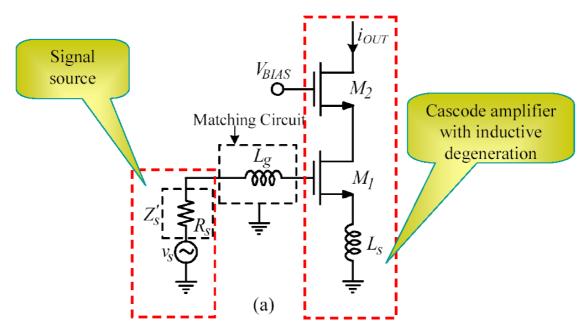
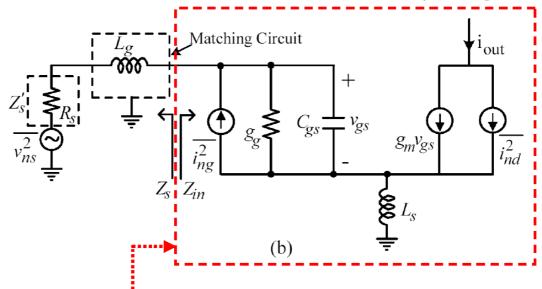


Fig. 3.2. (a) The schematic of cascode topology apply to adopt SNIM technique (b) Small signal equivalent circuit

Assume inductors are lossless, and matching circuit is implemented by a series inductor, but results are valid for arbitrary matching circuits.



Obtain noise parameters by applying KCL/KVL

#### 3.2.2. Noise Parameters

## The noise parameters are given by [Appendix]

## ✓ Noise Figure Expression

$$F = 1 + \frac{1}{g_{m}^{2}R_{s}} \cdot \begin{cases} \int \left[1 + s^{2}C_{gs}\left(L_{g} + L_{s}\right)\left(1 + |c|\alpha\sqrt{\frac{\delta}{5\gamma}}\right)\right]^{2} \\ -\left(sC_{gs}R_{s}\right)^{2}\left(1 + |c|\alpha\sqrt{\frac{\delta}{5\gamma}}\right)^{2} \\ -\frac{\alpha\delta}{5}\left(1 - |c|^{2}\right)g_{m}\left(sC_{gs}\right)^{2}\left(R_{s}^{2} - sL_{g}^{2}\right) \end{cases}$$
(3.9)

✓ Noise Resistance

$$R_n = R_n^o = \frac{\gamma}{\alpha} \cdot \frac{1}{g_m} \tag{3.10}$$

✓ Minimum Noise Figure

$$F_{min} = F_{min}^{o} = 1 + \frac{2}{\sqrt{5}} \frac{\omega}{\omega_{T}} \sqrt{\gamma \delta (1 - |c|^{2})}$$
(3.11)



Same as that of the CNM technique

## ✓ Optimum Noise Impedance

$$Z_{opt} = Z_{opt}^o - sL_s (3.12)$$

$$Z_{opt}^{o} = 1/Y_{opt}^{o} = \frac{\alpha\sqrt{\frac{\delta}{5\gamma(1-|c|^{2})}} + j\left(1+\alpha|c|\sqrt{\frac{\delta}{5\gamma}}\right)}{\omega C_{gs}\left\{\frac{\alpha^{2}\delta}{5\gamma(1-|c|^{2})} + \left(1+\alpha|c|\sqrt{\frac{\delta}{5\gamma}}\right)^{2}\right\}}$$
(3.13)

# • $L_s \rightarrow \text{No effect on Re}[Z_{opt}]$ , but cancel out $\text{Im}[Z_{opt}]$

✓ The input impedance  $Z_{in}$  can be expressed as

$$Z_{in} = sL_s + \frac{1}{sC_{gs}} + \frac{g_m L_s}{C_{gs}} = sL_s + \frac{1}{sC_{gs}} + \omega_T L_s$$
 (3.14)

 $\checkmark$  From Eq. (13), Eq. (12) can be re-expressed as

$$Z_{opt} = \text{Re}\left[Z_{opt}^{o}\right] - m\frac{1}{sC_{gs}} - sL_{s}$$
 (3.15)

- m = 0.6 for the typical device parameters of long channel
- m  $\approx$  1 with the advantage technologies (0.25 um CMOS, c  $\approx$  0.5,  $\alpha$  < 1 [39])
  - $\rightarrow L_s$  help to bring the  $Z_{opt} \approx Z_{in}^*$  while causing no degradation in  $F_{min}$  and  $R_n$

✓ The condition that allows simultaneous noise and input matching is

$$Z_{opt} = Z_{in}^* \tag{3.16}$$

✓ Or

$$Re[Z_{opt}] = Re[Z_s]$$
 (3.17)

$$\operatorname{Im}[Z_{opt}] = \operatorname{Im}[Z_s] \tag{3.18}$$

$$\operatorname{Im}[Z_{in}] = -\operatorname{Im}[Z_s] \tag{3.19}$$

$$Re[Z_{in}] = Re[Z_s]$$
(3.20)

# **Step-by-Step Design process**

- 1) For a given  $Z_s$ ,
- 2) Choose  $C_{gs}$  (or W) that satisfies  $Re[Z_{opt}] = Re[Z_s]$
- 3) Choose  $L_s$  that satisfies  $Im[Z_{opt}] = Im[Z_s]$
- 4) Choose  $V_{GS}$  that satisfies  $Re[Z_{in}] = Re[Z_s]$
- 5) Given  $L_s$  satisfies  $\text{Im}[Z_{in}^*] \approx \text{Im}[Z_{opt}]$  automatically
- $6) \rightarrow Z_{opt} = Z_{in}^* = Z_s$
- 7) If  $Z_s$  is not equal to  $Z_s$ , add matching circuit
- 8)  $\rightarrow$  Noise/input matched simultaneously for given  $Z_s$

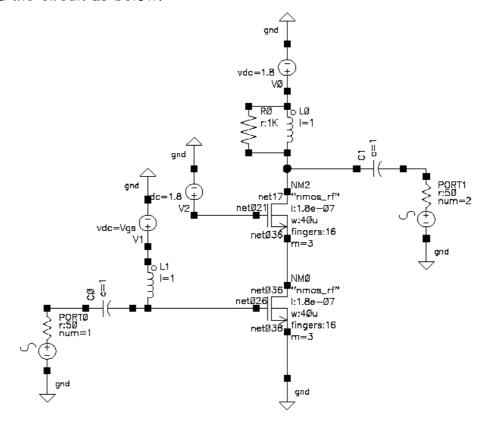
### 3.2.3. Design Process

The following steps describe the procedure how to design LNA based on cascode topology. Since there is no guideline how to choose the cascode transistor to obtain the best performances such as NF, Power gain, and Linearity. Assume that the size of cascode transistor is chosen to be equal to the input transistor. And also assume that the gate bias of the cascode transistor is  $V_{dd}$ .

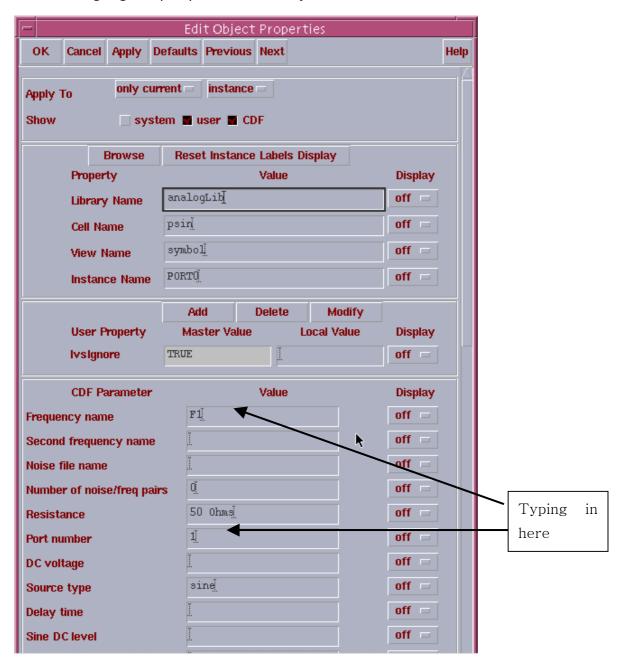
### 1) Choose V<sub>GS</sub>

### a) Setup Environment

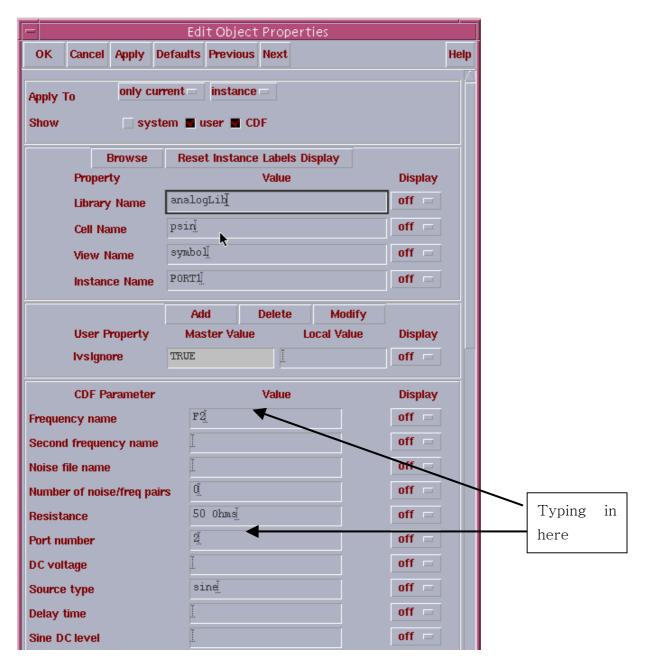
In the library named as LNA example, open new cell view named as Choose  $V_{\text{GS}}$ . Based on the knowledge conducted in the "Basis cadence lecture", build the circuit as below.



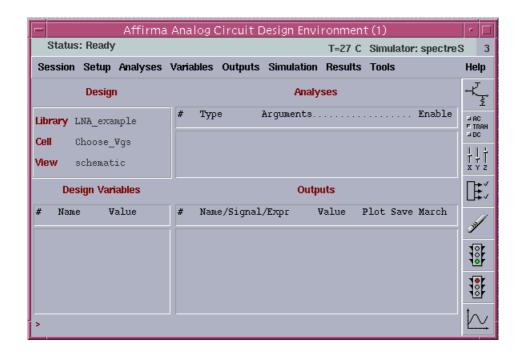
• Highlight input port and modify it as



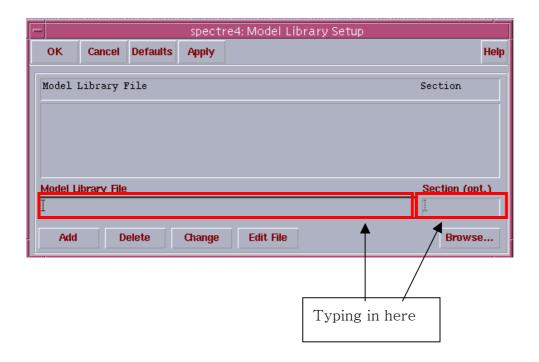
Highlight Output port and modify it as



• From the schematic window select: *Tool- Analog Environment* 



• On the Analog Circuit Design Environment, Click Setup-Model libraries

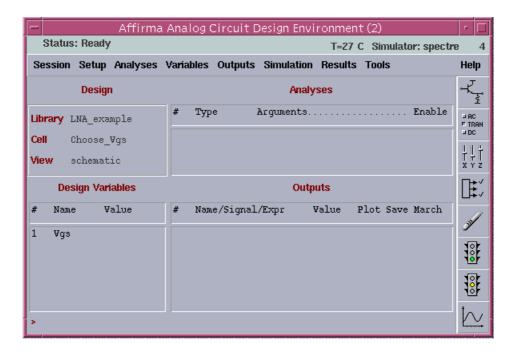


### • In the Model Library File and Section fields typing as following

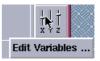
Model Library File	Section (opt.)
/data1/RACS/DC_project/Tsmc18/models/mm018.scs	tt
/data1/RACS/DC_project/Tsmc18/models/mm018.scs	tt_3v
/data1/RACS/DC_project/Tsmc18/models/mm018.scs	tt_na
/data1/RACS/DC_project/Tsmc18/models/mm018.scs	tt_3vna
/data1/RACS/DC_project/Tsmc18/models/mm018.scs	tt_m
/data1/RACS/DC_project/Tsmc18/models/mm018.scs	tt_3m
/data1/RACS/DC_project/Tsmc18/models/mm018.scs	ees
/data1/RACS/DC_project/Tsmc18/models/mm018.scs	tt_bip
/data1/RACS/DC_project/Tsmc18/models/mm018.scs	tt_bip3
/data1/RACS/DC_project/Tsmc18/models/mm018.scs	dio
/data1/RACS/DC_project/Tsmc18/models/rf018.scs	tt_rfmos
/data1/RACS/DC_project/Tsmc18/models/ResModel.scs	res_t

- ➤ You can Click *Browse* and go up to the directory, which contain the model library of the technology you would like to use. Or instructors will introduce the path of model library
  - Notice: After you finish typing one section, press Add icon. If you make some mistakes, you can delete by click Delete icon

- On the Analog Environment Window, Click Variable-Copy from cell view.
- > Analog Environment window looks like

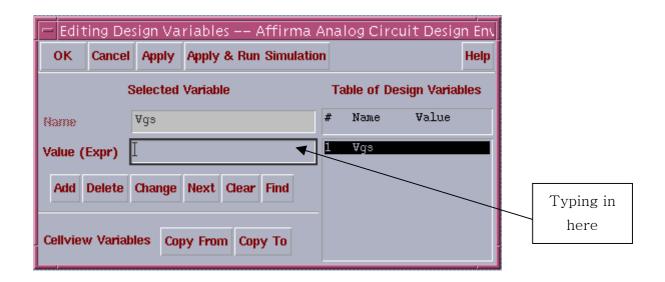


• Click edit variable icon on the right hand side

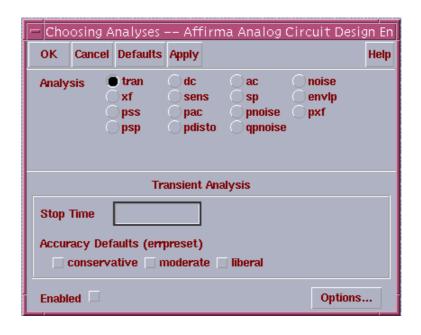


The following window will appear.

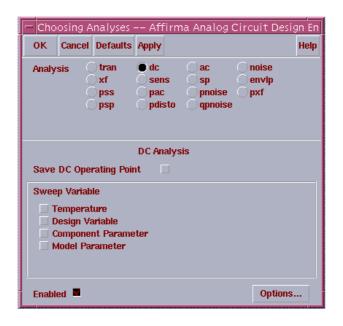
Highlight V<sub>GS</sub> and typing its primary value (any value)



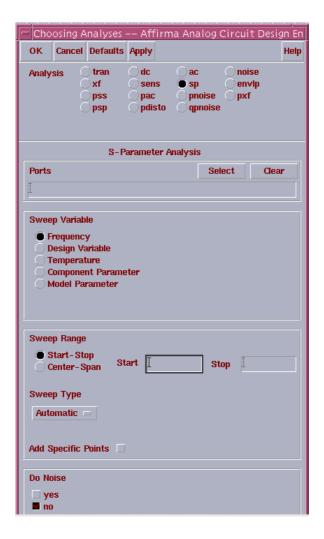
On the Analog Circuit Design Environment, select Analyses - Choose.
 The window will appear as



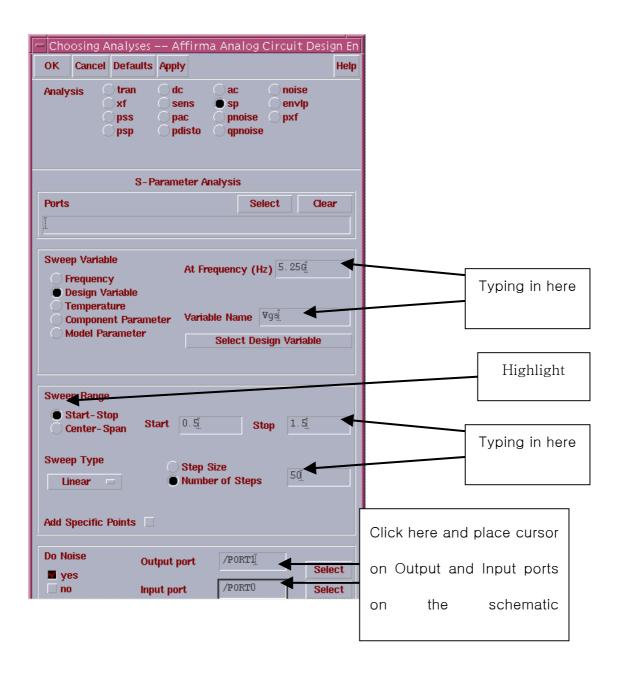
 On the choosing Analyses window, highlight DC simulator and modify the field as



- Click *Apply* icon.
- Choose SP Simulator, the window appear as



Modify your window to become as follows

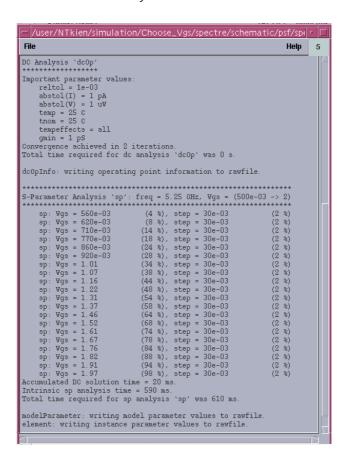


#### Click OK

#### b) Run simulation

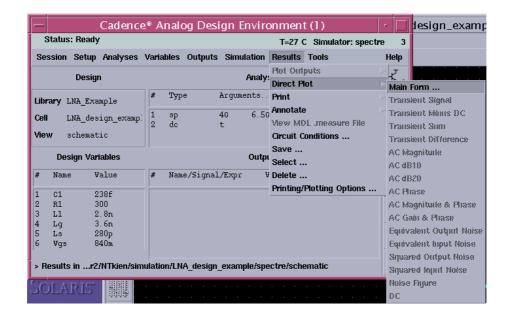


- Click Netlist and Run icon
- · After simulation is finished you can see the window looks like



### c) Plotting Results

• In the Simulation window, select *Results* → *Direct Plot* → *Main* Form.

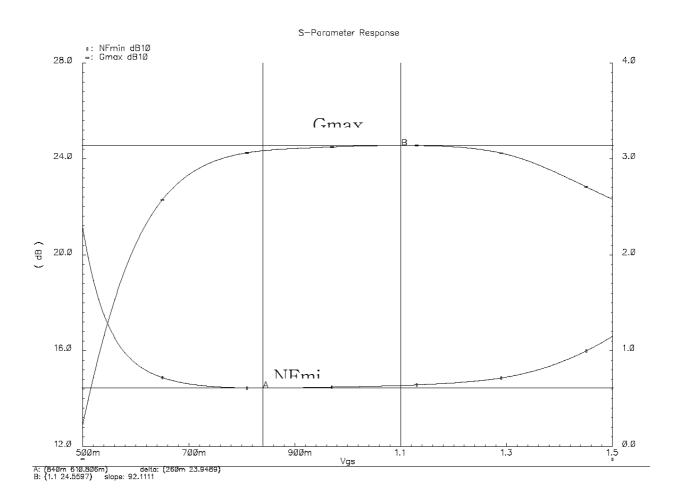


The window will appears as



On the SP-Parameters Result Form, do following

- Highlight Append for Plot Mode
- Highlight Gmax for Function
- Highlight *Rectangular* for *Plot Type*
- Highlight dB10 for Modifier
- Click *Plot*
- Choose *NFmin* for *Function*
- Highlight Rectangular for *Plot Type*
- Highlight dB10 for Modifier
- Click Plot



From above figures, we can determine the value of  $V_{\text{gs}}$  that gives the minimum

NF and maximum available gain. As can be seen in this figure, we choose  $V_{\text{gs}} = 840 \text{ mV}$ .

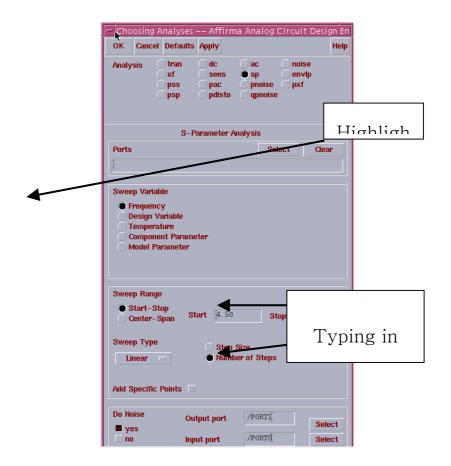
#### 2) Choose Size of Transistor

**Choose the size of transistor by simulating**  $\Gamma_{opt}$  = 50 Ω factor

#### a) Setup environment

We can set the multiplier factor of transistor as a variable and do the simulation to find the optimum value. But in this process the multiplier cannot be a variable therefore we have to do some simulation steps to find the optimum value of multiplier factor.

- > Setting the simulation window as
  - Setting V<sub>gs</sub> = 840 mV.
  - Modify SP simulator as below.



• Click OK

#### b) Run Simulation



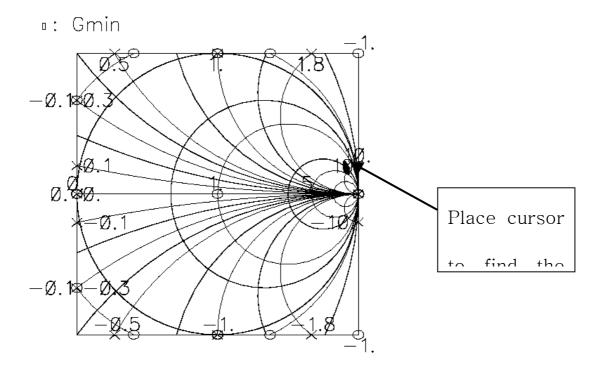
• Click Run simulation icon

#### c) Plotting Results

- After simulation finish click Results  $\rightarrow$  Main For  $\rightarrow$  S-parameters.
- On the *S-Parameter* Results window do following
  - Choose Gmin (Optimum noise Reflection Coefficient) for Function
  - Choose *Z-Smith* for *Plot Type*



#### • Click Plot

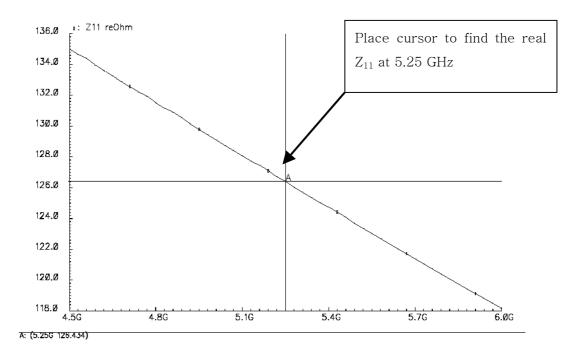


#### Another way to see the result

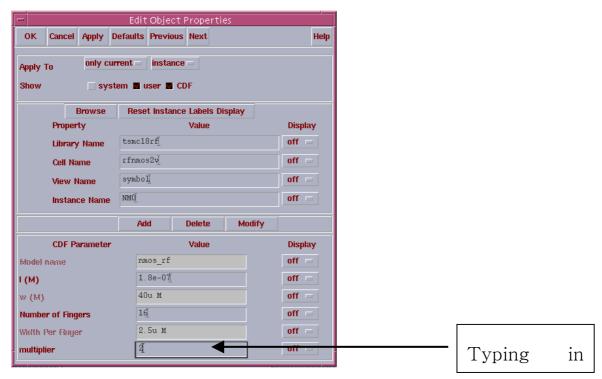
- On the Analog Circuit Design Environment, do following
  - Highlight ZP (Z parameters) for Function
  - Highlight *Rectangular* for *Plot Type*
  - Highlight *Real* for *Modifier*



Click Z11 we can see the results as below



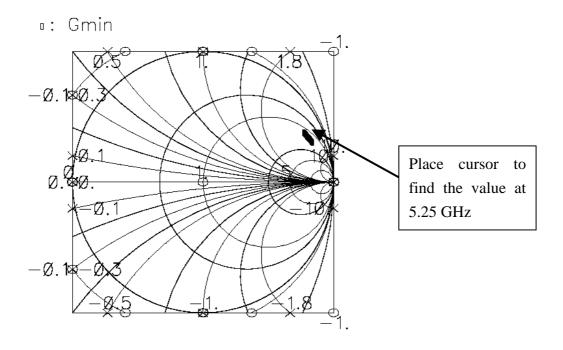
- > On the Schematic window do following
  - Highlight NMOS transistor by press Q
  - On the properties window, change *multiplier* = 2.



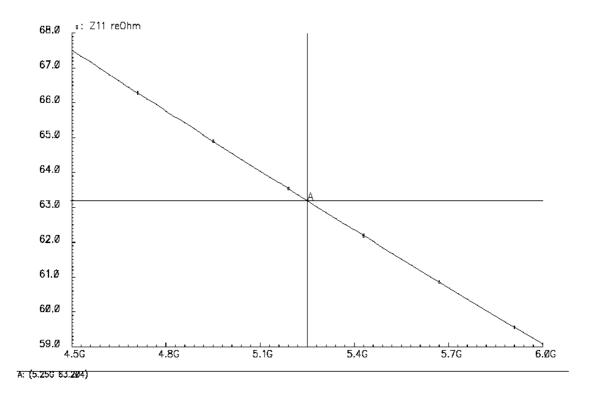
• Press OK

#### • Press Save and Check icon

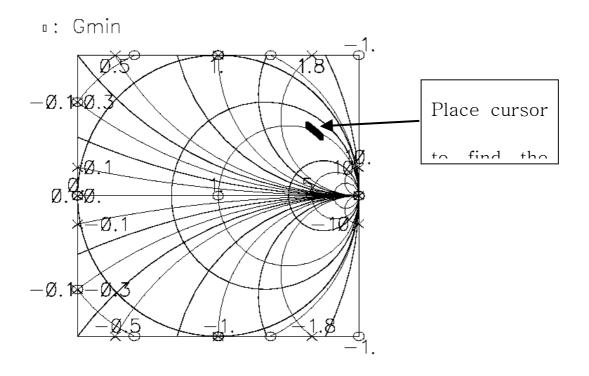
Run simulation and plot result (do the same steps as previous)

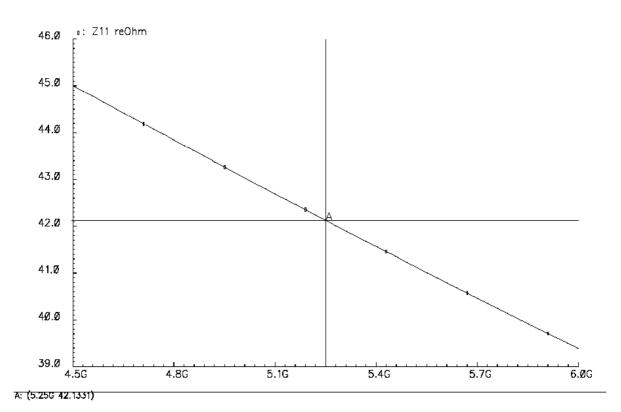


• Do the same step to plot the Z11

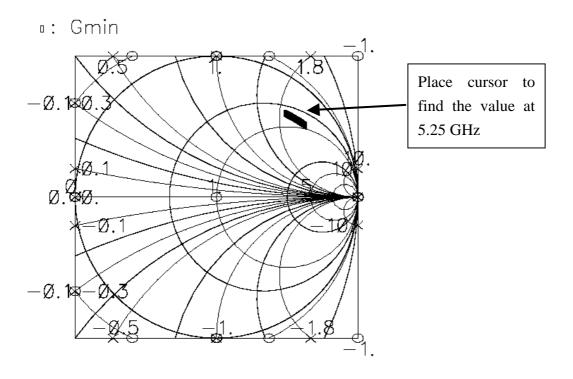


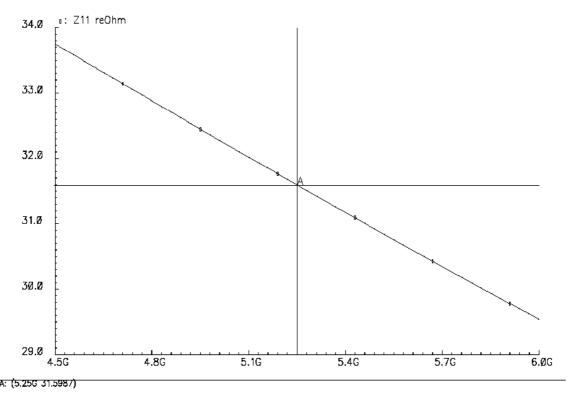
• Do the same above steps for *multiplier* = 3, you obtain the result as





• Do the same above steps for *multiplier* = 4, you obtain the result as





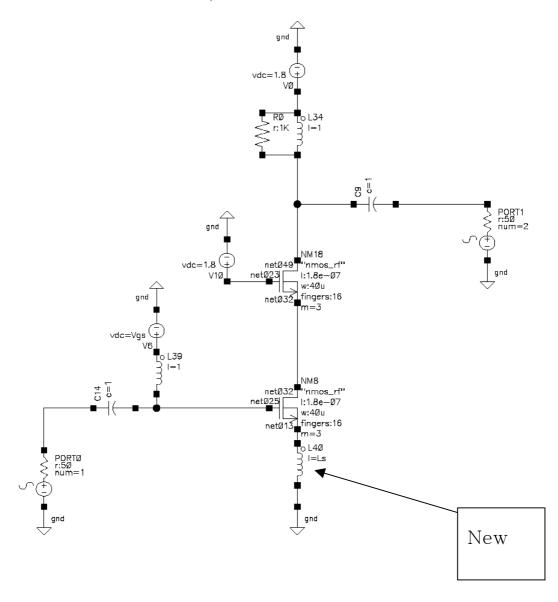
As can be seen from above figures, when **multiplier** factor = 3, the real part of  $G_{\text{min}}$  = 1.

### 3) Choose L<sub>s</sub> (Inductor Degeneration)

This step is to choose the value of  $L_{\text{s}}$  that makes the real part of  $S_{11}$  = 1

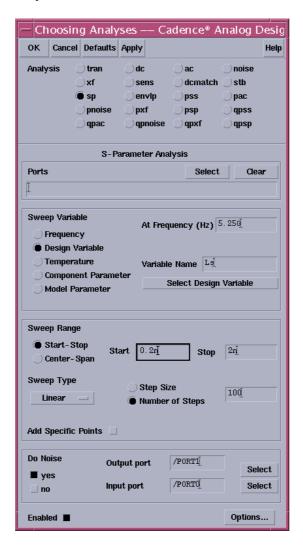
### a) Setup Environment

• In the schematic window, insert new inductor as below

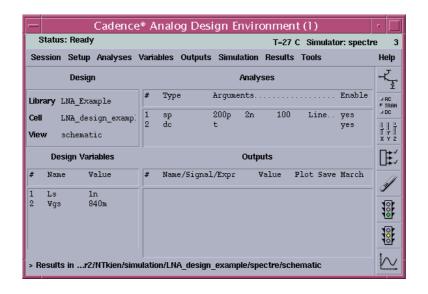


- A new inductor has inductance value as Ls
- On the Analog Circuit Design Environment do the following
  - Select Variables Copy From Cell View
  - Setting primary value of Ls (any value)

Modify SP simulation looks like



- Click OK
- Now your Circuit Design Environment looks like



### b) Run Simulation



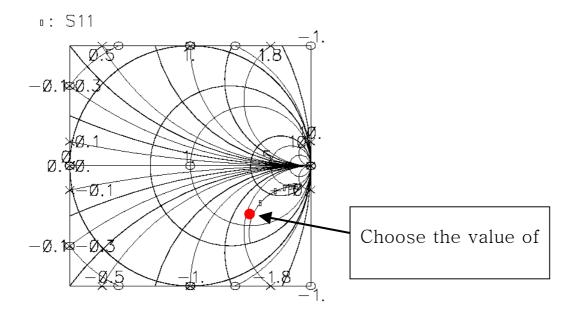
> Click Netlist and Run icon

### c) Plotting Results

- ➤ After finish simulation, select *Results* → *Direct Plot* → *Main Form*
- > On the S-Parameter Results window do following
  - Highlight SP (S parameters) for Function
  - Highlight *Z-Smith* for *Plot Type*



> Click S11, you can see the result as below

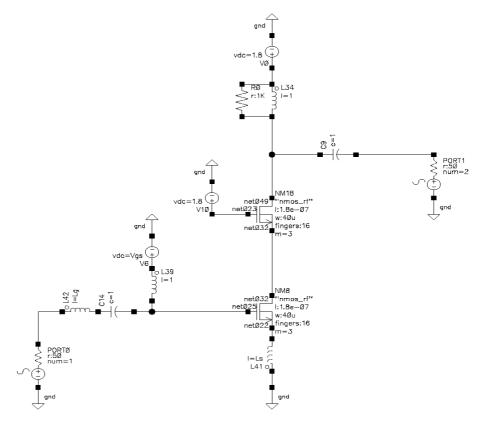


From this figure, you obtain the value of  $L_s$  = 0.28 nH

## 4) Choose the series gate inductance

## a) Setup environment

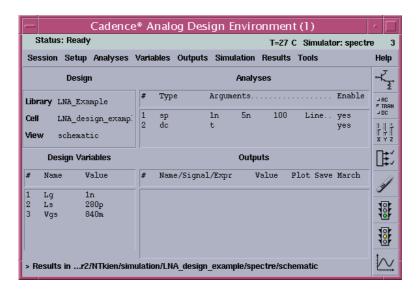
• Insert new inductor which has the inductance value = Lg.



- On the Analog Circuit Design Environment, do the following
  - Change the value of  $L_s = 0.28 \text{ nH}$ .
  - Select Variable Copy From Cell View.
  - Set the primary value of Lg (any value)
  - In the Analog Circuit Design Environment, double click on the SP simulation and modify as



- Click OK
- Now the Analog Circuit Design Environment becomes as below



### b) Run Simulation



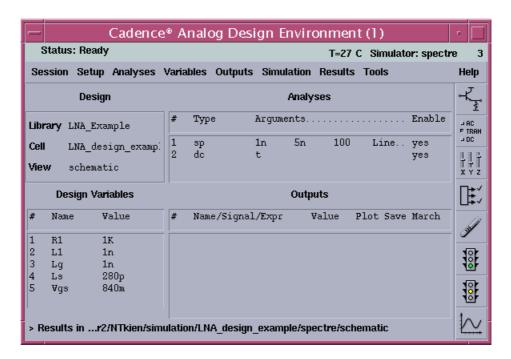
- Click Nestlist and Run icon
- c) Plotting Results
  - After finish simulation, select Results → Direct Plot → Main Form → Sparameters.
  - On the S-Parameter Results window do following
    - Highlight SP (S parameters) for Function
    - Highlight Z-Smith for Plot Type



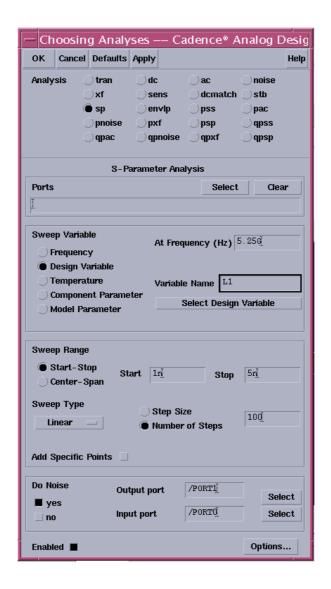
• Click S11, you can see the result as below

# 

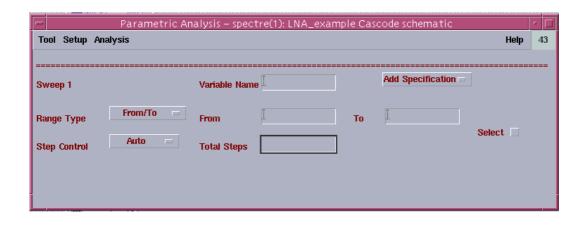
- 5) Output Matching: Choose load inductance and load resistance
- a) Setup environment
  - On the Schematic Window do following steps
    - Change the value of the load resistor to become R1
    - Chang the value of the load inductor to become L1
  - On the Analog Circuit Design Environment do following
    - Click Variables → Copy From Cell View
    - Set the *primary value* of L1 and R1 (any value)
    - The Analog Design Environment look like



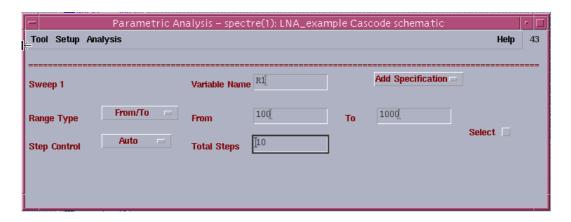
• Double Click on the SP simulator and modify it as



> Select Tools - Parametric Analysis, the following window appears



Modify the window as below

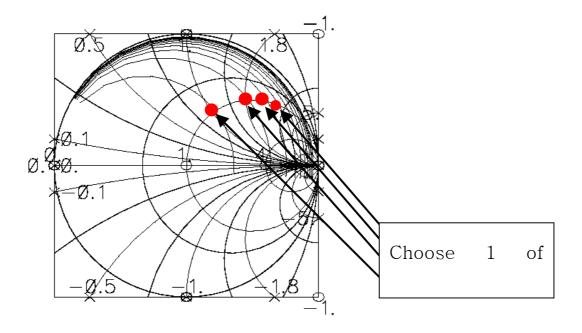


#### b) Run Simulation

• On the Parametric Analysis window, select *Analysis - Start* 

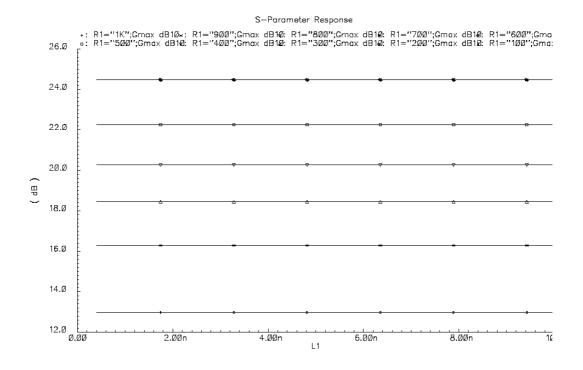
## c) Plotting Results

- · After simulation is finished, Plotting result
- ➤ On the Analog Circuit Design Environment, choose: Results → Direct Plot → Main Form → S-parameters, the SP-Parameters window will appear
  - Highlight *SP* for *Function*
  - Highlight Z-Smith for Plot Type
  - Click S22 button



You can choose 1 of the ten values that is shown in above figure, however, you should consider about the maximum available gain at each value.

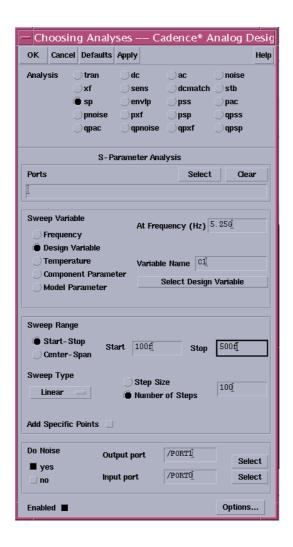
 On the Analog Circuit Design Environment, plotting Gmax as the function of R1 and L1



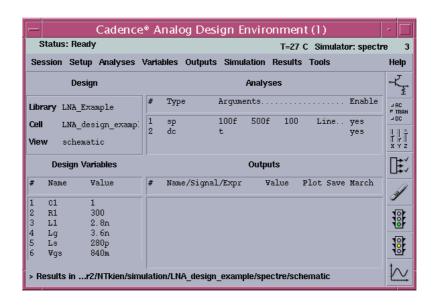
- ➤ Based on above figure, assume that you decide to design LNA has gain around 18, so result shows the value of R1 = 300 Ohm.
- ➤ See in the Smith chart, when the R1 = 300 Ohm → L1 = 2.8 nH
- 6) Output Matching: choose output capacitance

#### a) Setup environment

- ➤ On the schematic window, *highlight* capacitor named *C1* and setting its *capacitance* value = C1.
- > On the Analog Circuit Design Environment, do following
  - Select Variable Copy From Cell View.
  - Set the primary value of C1 (any value)
  - Change the value of L1 = 2.8 nH (this result is obtained in the previous simulation step)
  - On the Analog Circuit Design Environment window, double click on the SP simulation and modify as



Now your Analog Circuit Design Environment looks like below



#### b) Run simulation

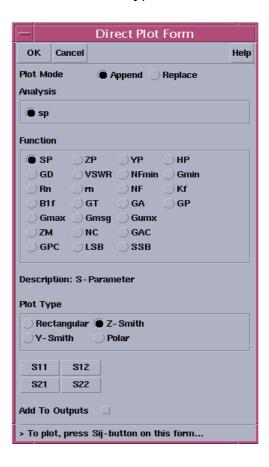
> Click Netlist and Run icon



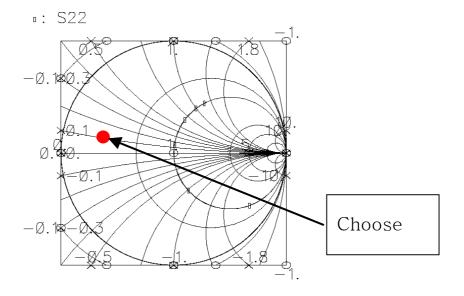
#### c) Plotting result

After finish simulation, select Results → Direct Plot → Main Form → S
Parameters

- > On the S-Parameter Results window do following
  - Highlight SP for Function
  - Highlight *Z-Smith* for *Plot Type*



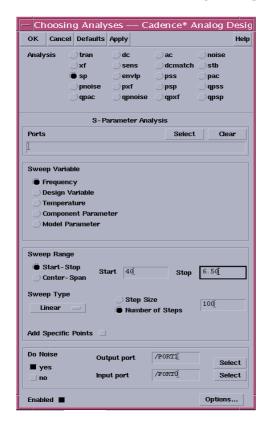
> Click \$22 button, you can see the result as below



## 7) Running S-Parameters and NF Simulation

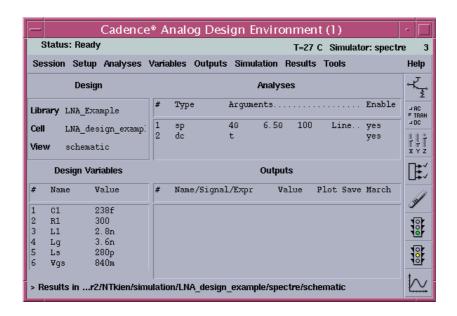
## a) Setup Environment

- > On the Analog Circuit Design Environment window, do following
  - Change the value of C1 = 238 fF
  - Double click on SP simulator and modify it as



Click *OK* 

> Now the Analog Circuit Design Environment looks like below



#### b) Run simulation

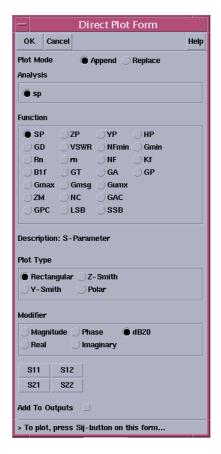


Click The Netlist and Run icon to run the simulation

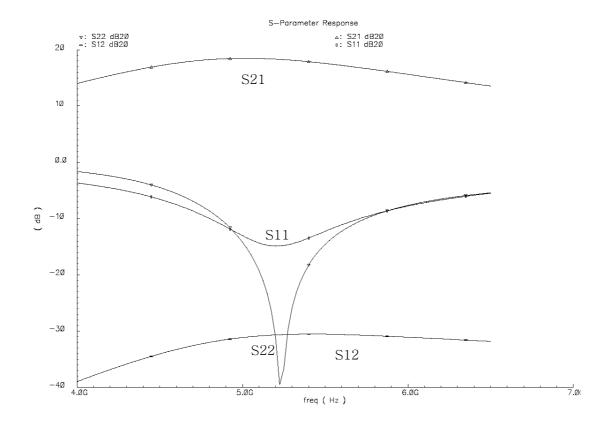
- c) Plotting Results
  - Plot S parameters:

On the Analog Design Environment window

- ➤ Click Results → Direct Plot → Main Form → S Parameters
- > Modify *Direct Plot Form* window as follows



> Click on S11, S22, S21, and S12 separately, the results are shown as follows



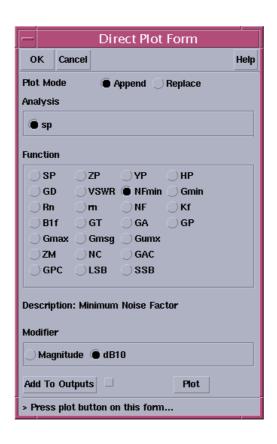
As can be seen in above Fig., the value of S11 is high because the limitation of the isolation between output and input. However, the value of S11 = 15 dB, it can be accepted. If the value of S11 is higher than -15dB, the designer might have to do some simulation steps.

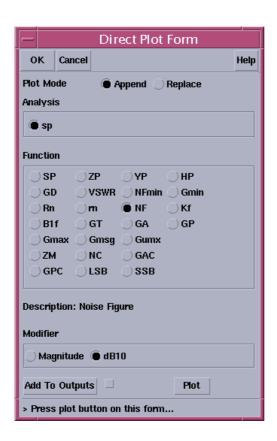
- Keep the output matching as the condition which is found at step (5) &(6)
- Find the value of Ls as the step (3).
- Find the value of Lg as the step (4)

#### Plot NF and NFmin of LNA

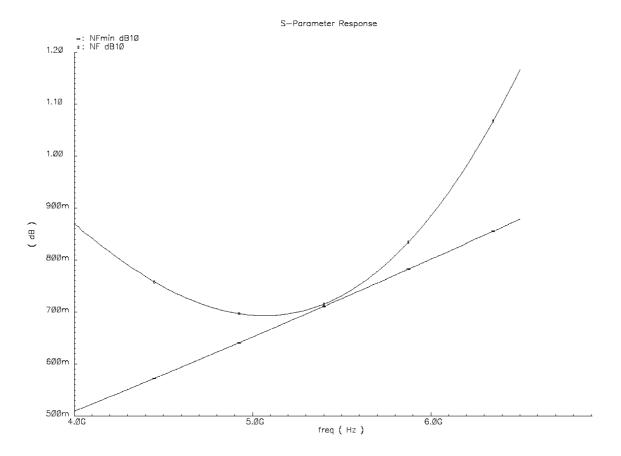
On the Direct Plot Form

- > Highline *NFmin* (or *NF*) at the function field
- Highline dB10 for Modified





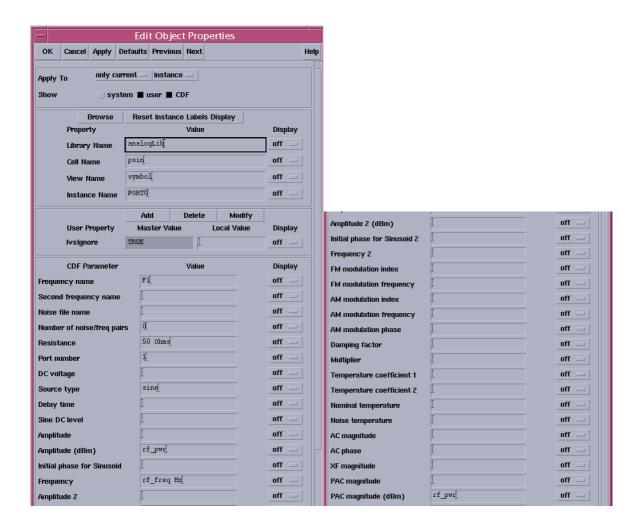
The results are shown as follows



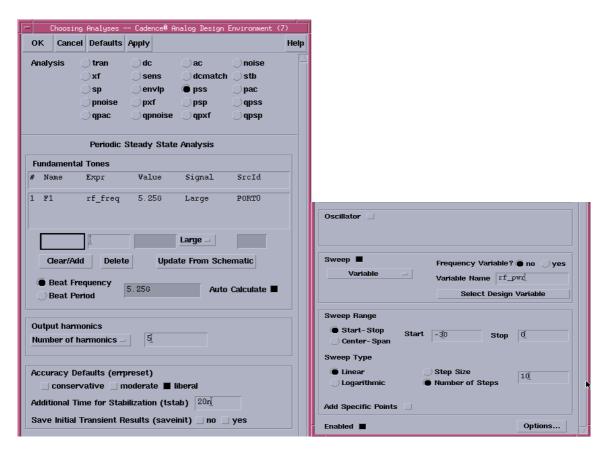
As can be in above Figures, the value of the NF is slightly higher than  $NF_{min}$  of the given topology. The reason is the size of the input transistor cannot be chosen properly.

(See the choosing transistor size step, step (2))

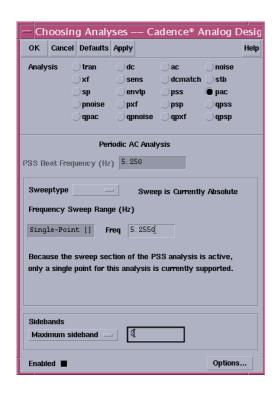
- 8) Linearity simulation (IIP3 and 1 dB compression Point)
- a) Setup environment
- > On the schematic window, highlight input Port and modify it as



- On the Analog Circuit Design Environment do following
- Select Variable Copy From Cell View
- Setting the primary value of *rf\_freq* and *rf\_pwr* to be 5.25 G and -40
- Select Analyses Choose
- Highlight PSS and modify it as below

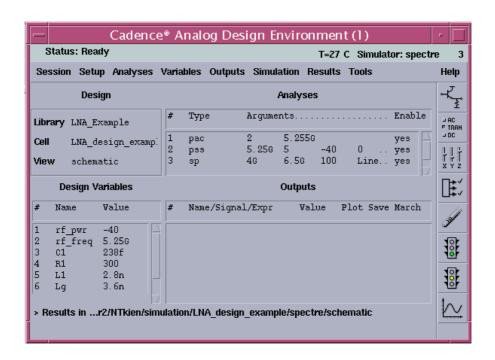


Highlight PAC on the Choosing Analyses window an modify it as



> Click *OK* on the *Choosing* Analyses window.

• Your Analog Circuits Design Environment looks like



#### b) Run simulation

> To run SP analysis, click Netlist and Run icon

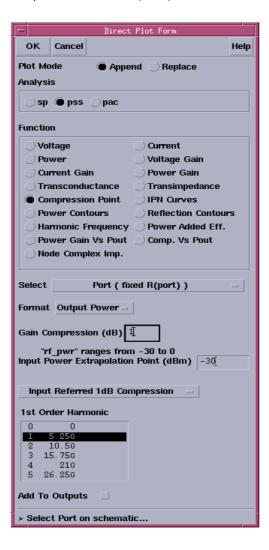


Look in the output log file to be sure the simulation is completed successfully.

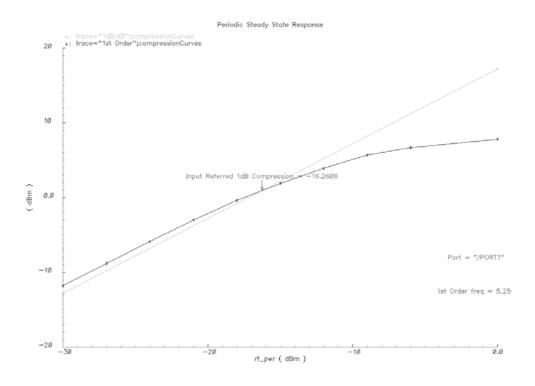
#### c) Plotting Results

- Plotting 1 dB compression point
- $\blacktriangleright$  In the simulation window, choose *Results*  $\rightarrow$  *main Plot*  $\rightarrow$  *PSS*. The Waveform window and PSS results form appear.
- In the PSS results, highlight *PSS* for *Analysis Type*
- In the PSS results, highlight *Compression* point for *Function*

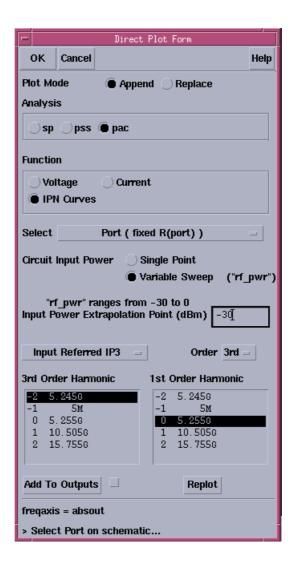
> Highlight Variable Sweep for circuit input power



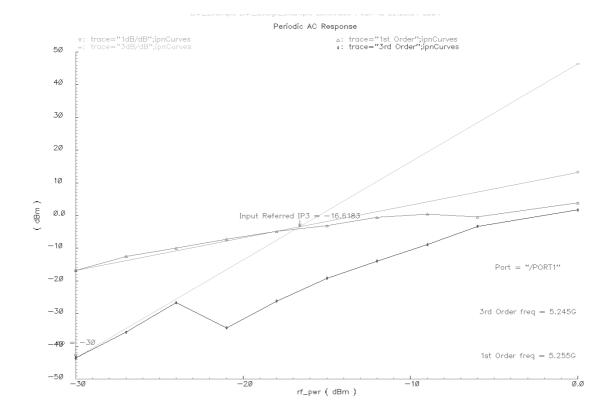
> Place cursor in the schematic window and click on the output port.



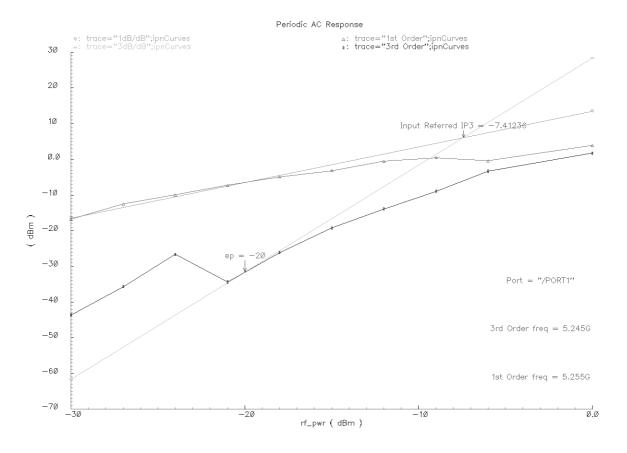
- Plotting IIP3
- On the Analog Circuit Design Environment window, choose: Results →
   Direct Plot → PSS. The waveform window and the PSS results appear
- Highlight PAC and modify it as



 Place cursor on the output port in the schematic window, you will see the result as



## ➤ If we choose the Extrapolation value is -20, then we obtain the following Fig.



# ✓ SNIM technique is applicable for any $Z_s$ with assuming

$$\begin{split} R_n &= R_n^o = \frac{\gamma}{\alpha} \cdot \frac{1}{g_m} \quad , \quad Z_{opt} = Z_{opt}^o - sL_s \\ F_{min} &= F_{min}^o = 1 + \frac{2}{\sqrt{5}} \frac{\omega}{\omega_T} \sqrt{\gamma \delta (1 - |c|^2)} \end{split} \qquad \begin{aligned} &\text{Stays valid with} \\ &\text{large $W$, high $P_D$} \\ &\text{and $\omega$} \end{aligned}$$

- $\checkmark$  Problem occurs with small  $W(\text{low }P_D)$  and low  $\omega$ 
  - $\rightarrow$  increase  $\text{Re}[Z_{opt}] \rightarrow$  requires high  $\text{Re}[Z_{in}^*] = \text{Re}[Z_{opt}]$
  - $\rightarrow$  requires high  $L_s \rightarrow$  makes the expression for  $F_{min}$  invalid
  - $\rightarrow$   $F_{min}$  increase significantly above  $F_{min}{}^{o}$
- ✓ Even with small W, low  $P_D$ , and low  $\omega$ , possible to achieve  $Z_S = Z_{in}^*$  with  $L_s$  but NF >  $F_{min}^o$
- ✓ SNIM technique is not applicable for W,  $\omega$ , and  $P_D$  where  $\text{Re}[Z_{opt}]$  becomes greater than  $\text{Re}[Z_{in}]$  for the maximum value of  $L_s$  ( $L_{s,\text{max}}$ ) where  $F_{min}$  of the LNA is not degraded
- ✓  $L_{s,max}$  can be identified by monitoring  $F_{min}$  vs.  $L_s$
- $\checkmark$  There exists an optimum W that provides minimum

NF  $(> F_{min}^{\ \ o}) \rightarrow$  Power-Constrained Noise Optimization Technique

- 3.3. Power Constrained Noise Optimization Technique
  - ✓ Under fixed drain current, there exist a transistor size where the NF become minimum [Shaeffer].

$$W_{opt} \approx \frac{1}{3\omega C_{ox} R_s Q_{in\ opt}}$$
 (3.21)

$$Q_{in,opt} = \left| c \middle| \sqrt{\frac{5\gamma}{\delta}} \left[ 1 + \sqrt{1 + \frac{3}{\left| c \right|^2} \left( 1 + \frac{\delta}{5\gamma} \right)} \right]$$
 (3.22)

✓ The minimum NF of this case is given by

$$F_{minP} \approx 1 + 2.4 \frac{\gamma}{\alpha} \left[ \frac{\omega}{\omega_T} \right]$$
 (3.23)

✓ Compare to Eq. (12),  $F_{minP}$  is higher than  $F_{min}$ .

$$F_{minP} \approx 1 + 2.4 \frac{\gamma}{\alpha} \left[ \frac{\omega}{\omega_T} \right]$$

$$F_{min} = F_{min}^o = 1 + \frac{2}{\sqrt{5}} \frac{\omega}{\omega_T} \sqrt{\gamma \delta (1 - |c|^2)}$$

- ✓ The reason is mismatch between  $Z_s$  and  $Z_{opt}$  and/or higher of  $L_s$  leads to higher  $F_{min}$
- ✓ PCNO technique will eventually converge to the SNIM technique as the power consumption increases (satisfy Eqs. (17), (18), and (20))

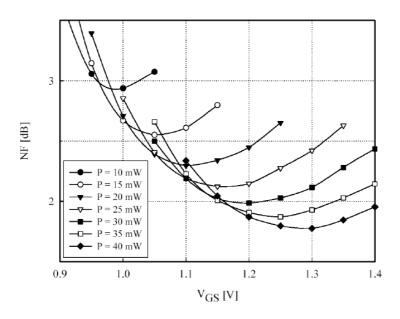


Fig. 3.3. The simulation of NF vs  $V_{GS}$  at various transistor size at 2 GHz based on 0.8 um CMOS

# 3.4. Power-Constrained Simultaneous Noise and Input Matching Technique

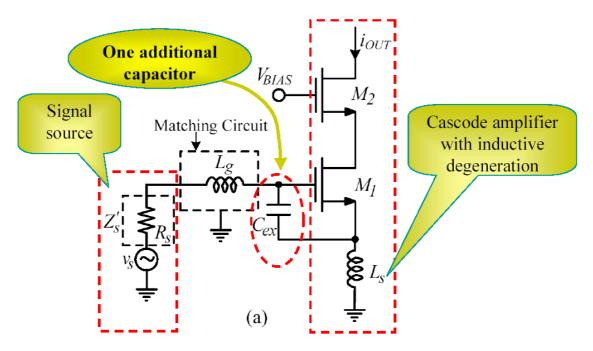
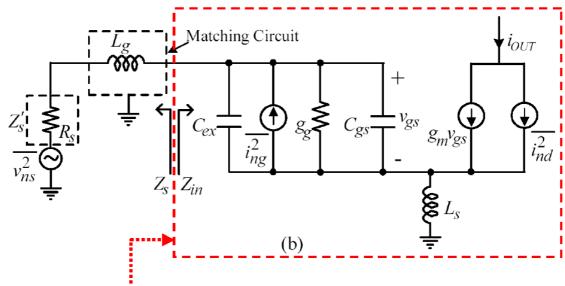


Fig. 3.4. (a) The schematic of cascode topology apply to adopt PCSNIM technique and (b) Small signal equivalent circuit

Assume inductors are lossless, and matching circuit is implemented by a series inductor, but results are valid for arbitrary matching circuits.



Obtain noise parameters by applying KCL/KVL

# The noise parameters are given by [Appendix]

$$F = 1 + \frac{1}{g_{m}^{2}R_{s}} \cdot \begin{cases} \int \left[1 + sC_{t}(sL_{g} + sL_{s})\left(1 + |c|\alpha\sqrt{\frac{\delta_{eff}}{5\gamma}}\right)^{2}\right] \\ -(sC_{t}R_{s})^{2}\left(1 + |c|\alpha\sqrt{\frac{\delta_{eff}}{5\gamma}}\right)^{2} \\ -\frac{\alpha\delta_{eff}}{5}(1 - |c|^{2})g_{m}(sC_{t})^{2}(R_{s}^{2} - sL_{g}^{2}) \end{cases}$$
(3.25)

✓ The mean-square gate-induce noise now is given by

$$\overline{i_{ng}^2} = 4kT \delta_{eff} \frac{\omega^2 C_t^2}{5g_{do}} \Delta f$$
(3.24)

where

$$\delta_{eff} = \delta . \left( C_{gs}^2 / C_t^2 \right)$$

$$C_t = C_{gs} + C_{ex}$$

 ✓ Apply the same derivation method as SNIM technique (See Appendix) → The noise parameters are given by

## **✓** Noise Resistance

$$R_n = \frac{\gamma}{\alpha} \cdot \frac{1}{g_m} \tag{3.26}$$

# ✓ Minimum Noise Figure

$$F_{min} = 1 + \frac{2}{\sqrt{5}} \frac{\omega}{\omega_{T,eff}} \sqrt{\gamma \delta_{eff} (1 - |c|^2)}$$

$$= 1 + \frac{2}{\sqrt{5}} \frac{\omega}{\omega_T} \sqrt{\gamma \delta (1 - |c|^2)}$$

$$[\omega_{T,eff} = g_m / (C_{gs} + C_{ex})]$$
(3.27)

Same as those of the CNM and SNIM techniques

# ✓ Optimum Noise Impedance

$$Z_{opt} = \frac{\alpha \sqrt{\frac{\delta}{5\gamma(1-\left|c\right|^{2})}} + j\left(\frac{C_{t}}{C_{gs}} + \alpha\left|c\right|\sqrt{\frac{\delta}{5\gamma}}\right)}{\omega C_{gs}\left\{\frac{\alpha^{2}\delta}{5\gamma(1-\left|c\right|^{2})} + \left(\frac{C_{t}}{C_{gs}} + \alpha\left|c\right|\sqrt{\frac{\delta}{5\gamma}}\right)^{2}\right\}} - sL_{s} \quad (3.28)$$

# ✓ From Fig. 4 (b), the input impedance is given by

$$Z_{in} = sL_s + \frac{1}{sC_t} + \frac{g_m L_s}{C_t}$$
 (3.29)

The condition for the simultaneous noise and input matching

$$Z_{opt} = Z_{in}^* - \operatorname{Re}[Z_{opt}] = \operatorname{Re}[Z_s] \operatorname{Im}[Z_{in}] = -\operatorname{Im}[Z_s]$$

$$\operatorname{Im}[Z_{opt}] = \operatorname{Im}[Z_s] \operatorname{Re}[Z_{in}] = \operatorname{Re}[Z_s]$$

$$\frac{\alpha\sqrt{\frac{\delta}{5\gamma(1-|c|^2)}}}{\omega C_{gs}\left\{\frac{\alpha^2\delta}{5\gamma(1-|c|^2)} + \left(\frac{C_t}{C_{gs}} + \alpha|c|\sqrt{\frac{\delta}{5\gamma}}\right)^2\right\}} = \operatorname{Re}[Z_s]$$
(3.30)

$$\frac{j\left(\frac{C_{t}}{C_{gs}} + \alpha |c| \sqrt{\frac{\delta}{5\gamma}}\right)}{\omega C_{gs} \left\{\frac{\alpha^{2} \delta}{5\gamma (1 - |c|^{2})} + \left(\frac{C_{t}}{C_{gs}} + \alpha |c| \sqrt{\frac{\delta}{5\gamma}}\right)^{2}\right\}} - sL_{s} = \operatorname{Im}\left[Z_{s}\right] \quad (3.31)$$

$$sL_s + \frac{1}{sC_t} = -\operatorname{Im}\left[Z_s\right] \tag{3.32}$$

$$\frac{g_m L_s}{C_t} = \text{Re}[Z_s]$$
 (3.33)

- ✓ Like SNIM technique, Eq.  $(3.31) \sim \text{Eq.}(3.32) \Rightarrow \text{Eq.}(3.32)$  can be dropped (for advanced technologies)
- ✓ The design parameters that can satisfy Eqs. (3.30), (3.31), (3.33) are  $V_{GS}$ , W,  $L_s$ , and  $C_{ex}$ 
  - $\rightarrow$  Eqs. (3.30), (3.31), (3.33) can be solved when power dissipation is fixed since three equations are provided by four unknowns
  - → the simultaneous noise and input matching can be achieved at any level of power dissipation

# Step-by-Step Design process

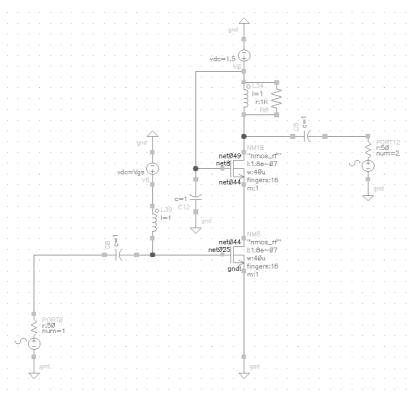
- 1) For a given  $P_D$  (power dissipation),
- 2) Choose  $V_{GS}$  from  $F_{min}$  vs.  $V_{GS}$  curve for an arbitrary transistor size (choose optimum  $F_{min}$ )
- 3) Choose  $C_{gs}(\text{or } W)$  to satisfy  $P_D \rightarrow \text{determines Re}[Z_{ont}]$
- 4) Choose  $C_{ex}$  and  $L_s$  to satisfy  $Re[Z_{in}] = Re[Z_{opt}]$
- 5) Given  $L_s$  satisfies  $Im[Z_{in}^*] \approx Im[Z_{opt}]$  automatically
- $6) \rightarrow Z_{ont} = Z_{in}^*$
- 7) Insert matching circuit to make  $Z_{opt} = Z_{in}^* = Z_s$
- 8) Noise/input matched simultaneously at given  $P_D$

#### 1) Power Constrained

Assume that we design LNA consuming 1 mW under supply voltage of 1.8 V.

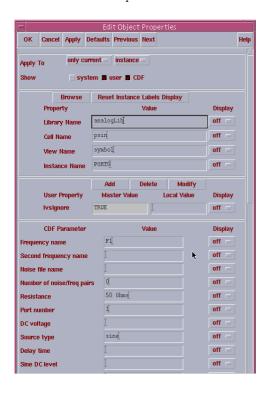
#### 1.1) Setup Environment

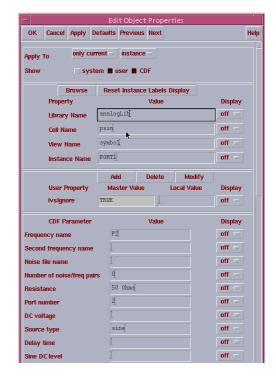
Draw Circuit as below



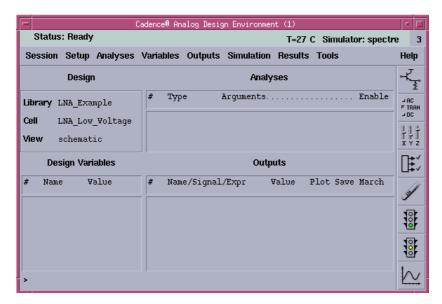
Modify Input Port and Output Port as follows Input Port

Output Port

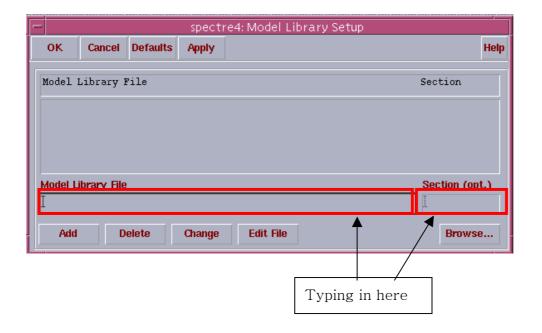




> From the schematic window select: Tool- Analog Environment



> On the Analog Circuit Design Environment, Click Setup-Model libraries

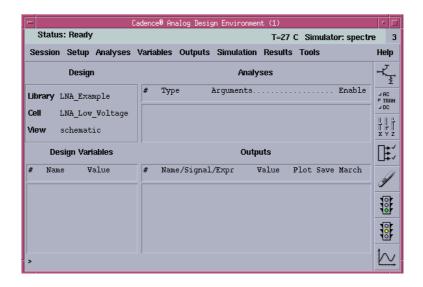


#### In the *Model Library File* and *Section* fields typing as follows

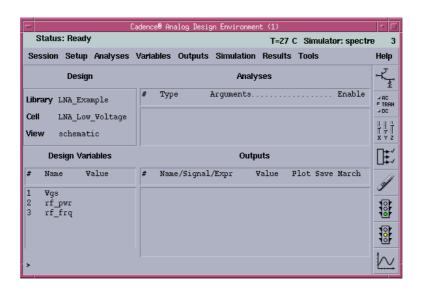
Model Library File	Section (opt.)
/data1/RACS/DC_project/Tsmc18/models/mm018.scs	tt
/data1/RACS/DC_project/Tsmc18/models/mm018.scs	tt_3v
/data1/RACS/DC_project/Tsmc18/models/mm018.scs	tt_na
/data1/RACS/DC_project/Tsmc18/models/mm018.scs	tt_3vna
/data1/RACS/DC_project/Tsmc18/models/mm018.scs	tt_m
/data1/RACS/DC_project/Tsmc18/models/mm018.scs	tt_3m
/data1/RACS/DC_project/Tsmc18/models/mm018.scs	ees
/data1/RACS/DC_project/Tsmc18/models/mm018.scs	tt_bip
/data1/RACS/DC_project/Tsmc18/models/mm018.scs	tt_bip3
/data1/RACS/DC_project/Tsmc18/models/mm018.scs	dio
/data1/RACS/DC_project/Tsmc18/models/rf018.scs	tt_rfmos
/data1/RACS/DC_project/Tsmc18/models/ResModel.scs	res_t

- You can Click Browse and go up to the directory, which contain the model library of the technology you would like to use. Or instructors will introduce the path of model library
  - Notice: After you finish typing one section, press Add icon. If you make some mistakes, you can delete by click Delete icon
  - On the Analog Environment Window, Click Variable-Copy from cell view.

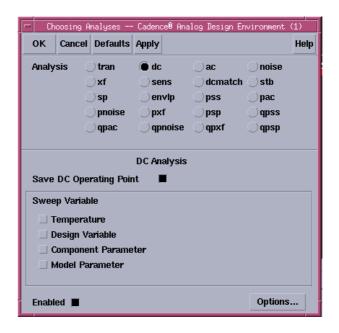
> Analog Environment window looks like



➤ Choose *Variable* → *Copy From Cell View*, Analog Environment window becomes



On the Analog Environment Window, Click Analysis-Choose, following windown will appear

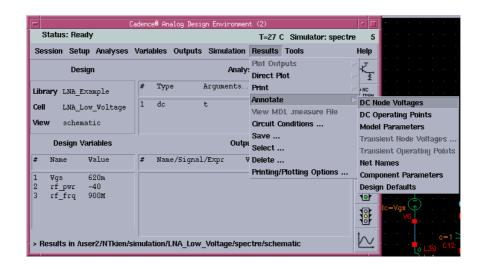


- ➤ Choose DC analysis
- Click on Save DC Operating Point
- > Make sure that *Enable icon* is on
- 1.2. Run Simulation
  - Click Netlist and Run icon



#### 1.3. Plot Results

From Analog Design Environment Windown, Click, *Results* → *Annotate* → *DC Node Voltage /DC Operating Points* 

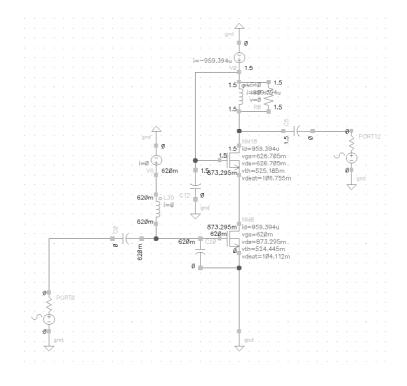


We can see the DC current dissipation of the circuit

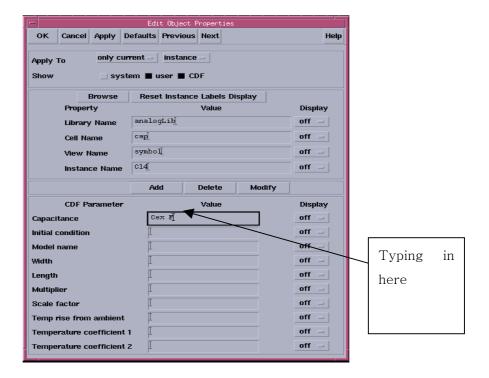
### 2) Choose the extral capacitor

#### a) Setup Inviroment

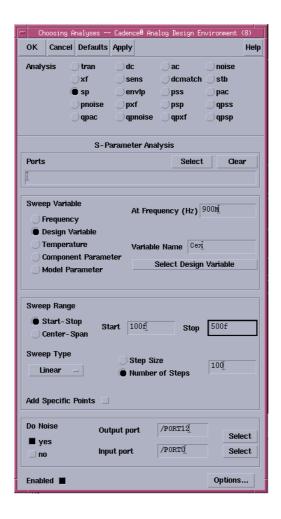
- > From the previous step, we choose the value of V<sub>GS</sub> is equal to 620 mV
- ➤ Insert one additional capacitor in parallel with Gate-Source capacitor of input transistor. The LNA schematic now becomes as follows



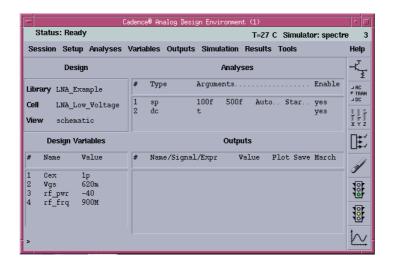
> Highline this additional capacitor and modify it as follows

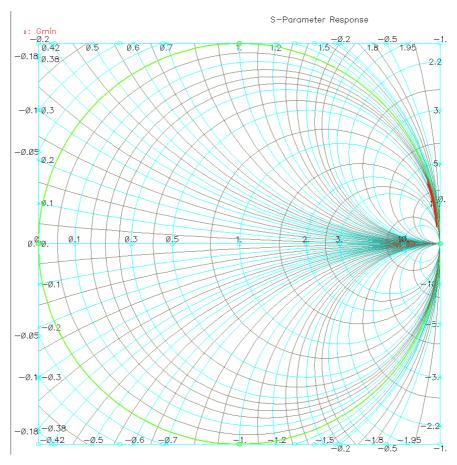


➤ From Analog Design Inviroment, click Analysis → Choose, the Choosing Analyses windown will appear, then modify it as follows



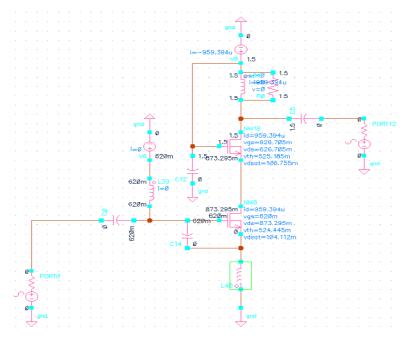
Click Apply and OK, then the Analog Design Environment windown becomes as follows

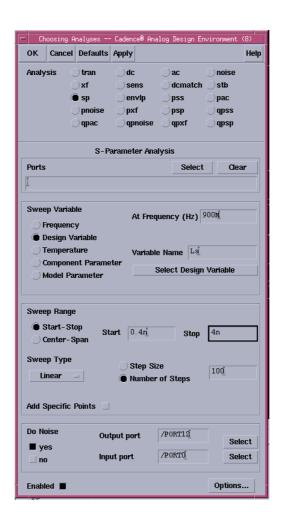


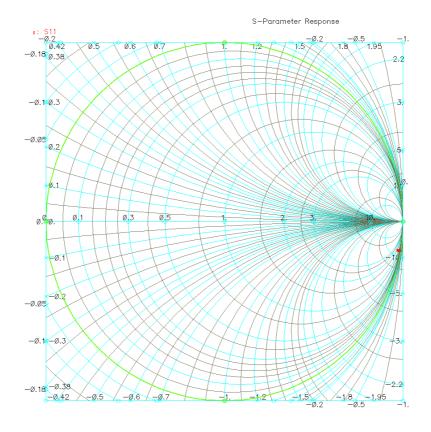


 $\blacktriangleright$  From above Fig., we can choose the value of  $C_{ex}$  = 210f in order to obtain the Real value of  $\Gamma$ opt equal to 1.

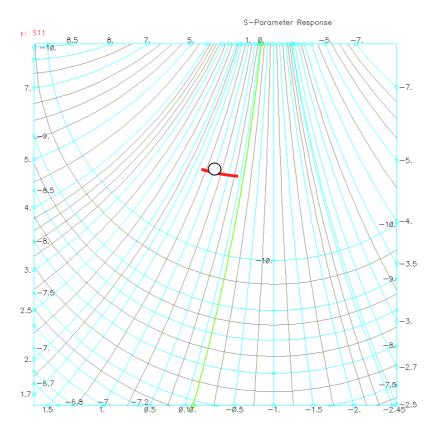
#### Insert inductive degeneration





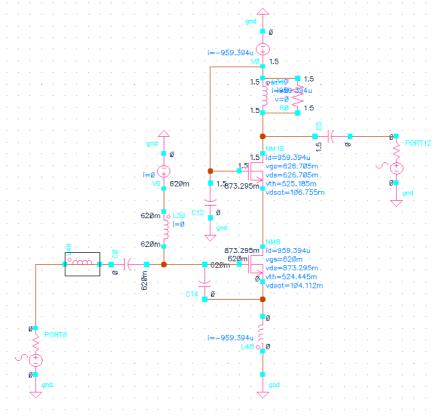


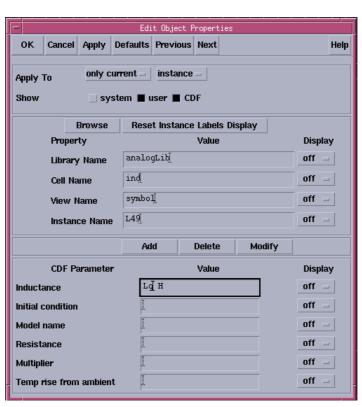
### Zoom in

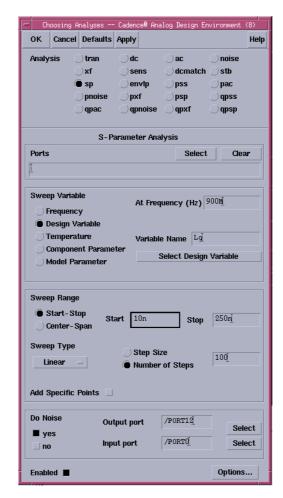


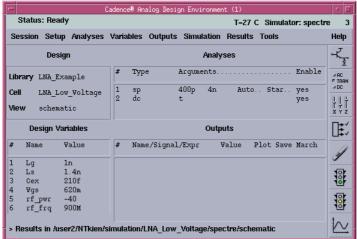
### Choose $L_s = 1.4n$

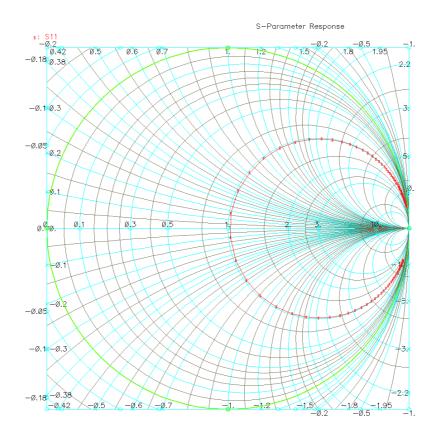
### Insert series gate inductor



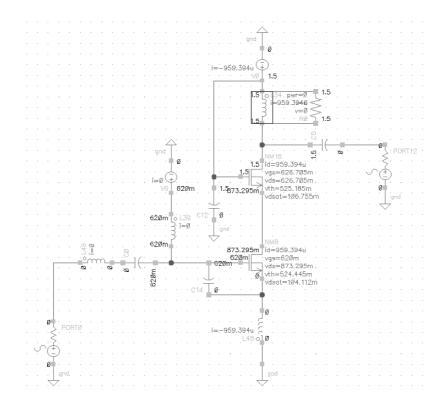




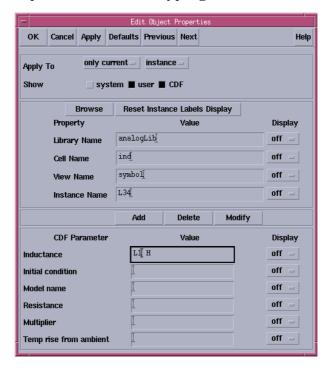


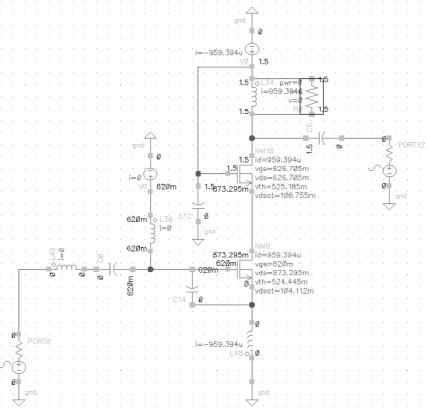


## Choose $L_g = 107 \text{ nH}$

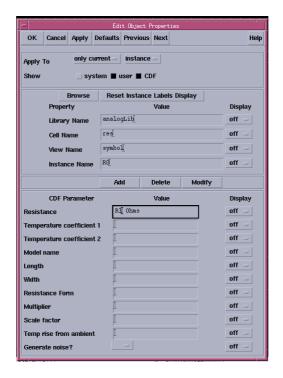


Highlight the output inductor and typing in the inductance field as L1

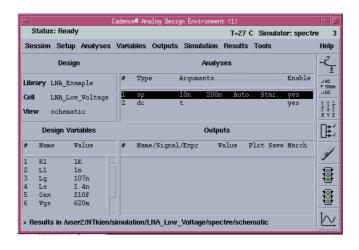


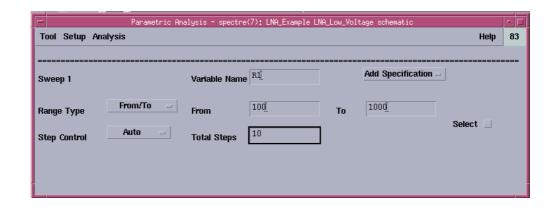


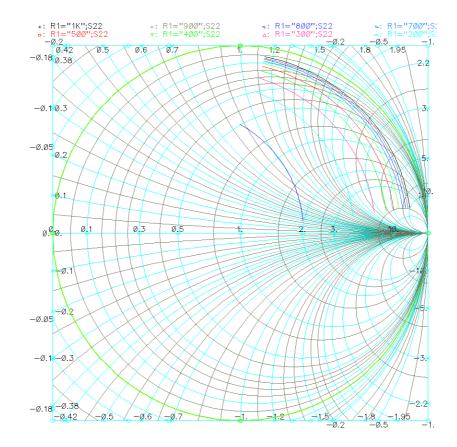
Highlight the output resistor and typing in the resistance field as L1

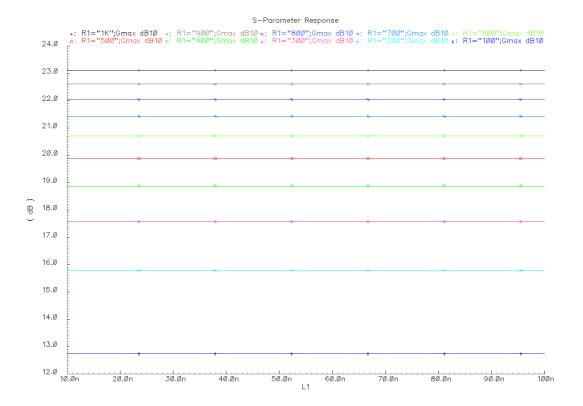


- ➤ On the Analog Design Environment, click Variable → Copy from cell view, and then typing the primalry value of L1 and R1 (any value).
- > The Analog Design Environment windown becomes



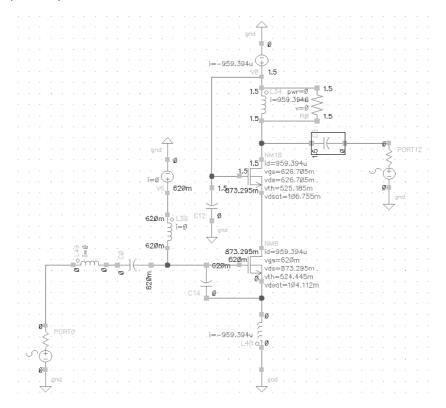


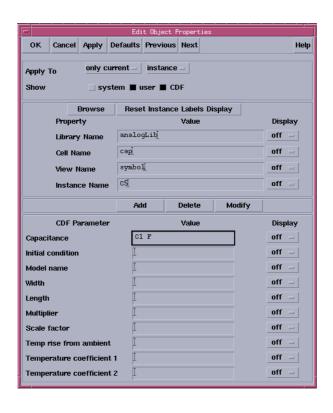


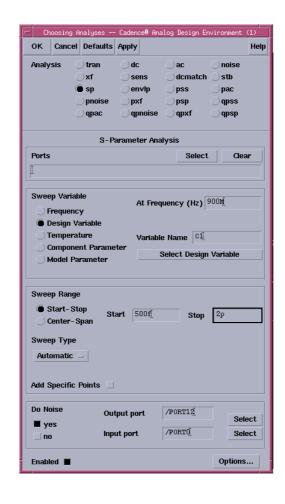


Choose R1 = 400 ohm, L1 = 26 nH

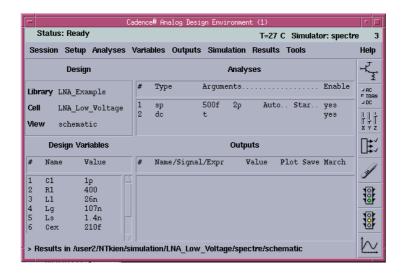
## Highline output capacitance

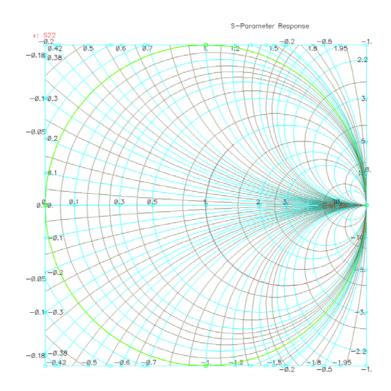






#### Analog Design Environment becomes



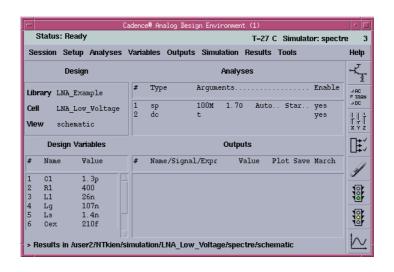


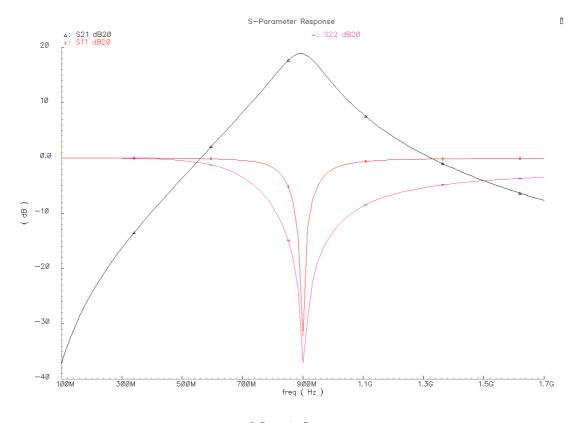
Choose C1 = 1.3 pF

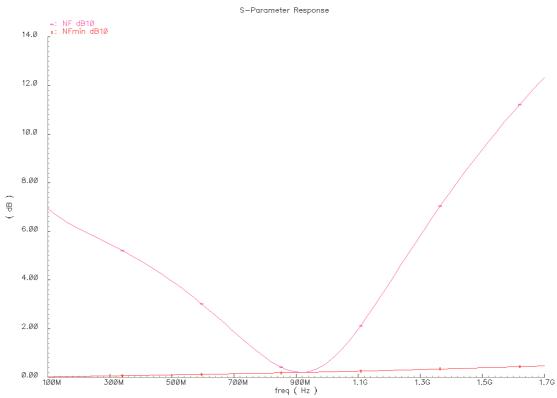
Run S-Parmeters Simulation



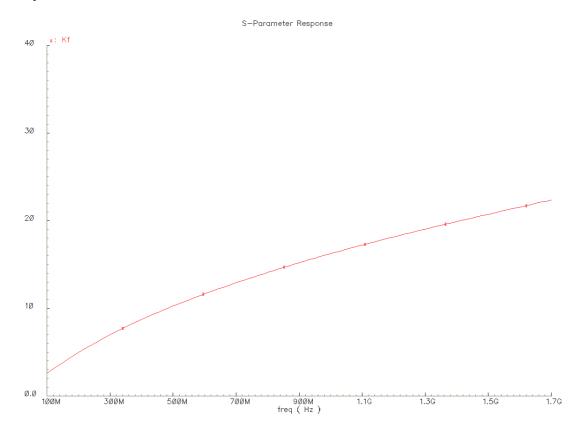
Analog Design Environment becomes







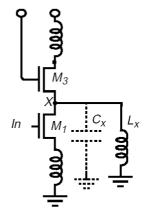
## Stability factor

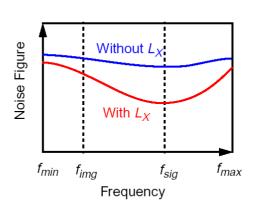


# 1. Image Rejection LNA

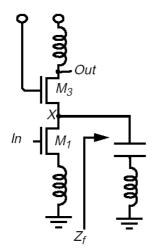
# 1.1 Circuit Descriptions

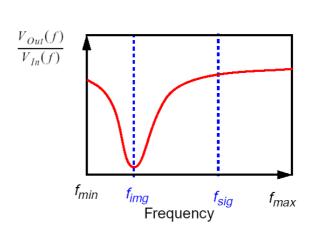
Parasitic capacitance  $C_X$  degrades the noise performance.



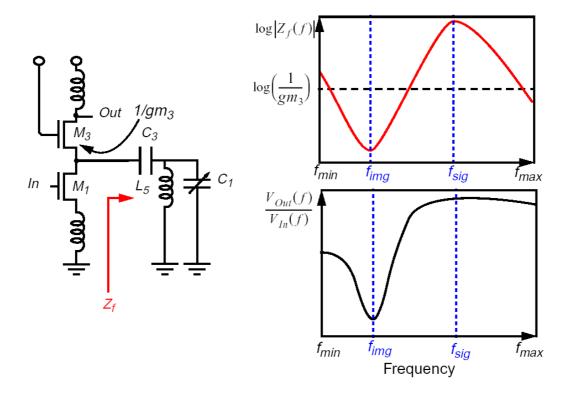


• Parallel resonance  $@f_{Sig} \rightarrow$  improves noise figure





• Series resonance  $@f_{lmg} \rightarrow$  improves image rejection



$$Z_{f}(s) = \frac{L_{5} \cdot (C_{3} + C_{1}) \cdot s^{2} + 1}{C_{1} \cdot C_{3} \cdot L_{5} \cdot s^{3} + C_{3} \cdot s}$$

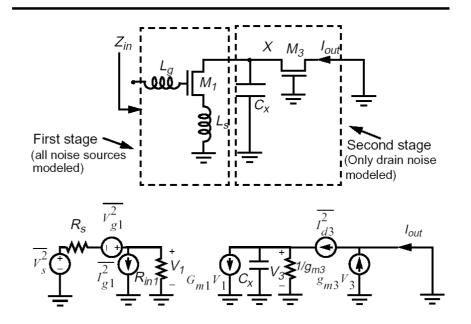
$$\omega_{p} = 0$$

$$\omega_{p} = \pm \frac{1}{\sqrt{L_{5} \cdot C_{1}}}$$

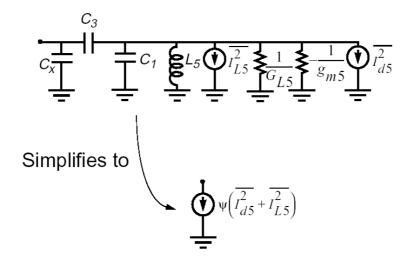
$$\omega_{z} = \pm \frac{1}{\sqrt{L_{5} \cdot (C_{3} + C_{1})}}$$

$$Z_{f}$$

# Equivalent Noise Circuit for the LNA



# Filter Noise Model



# **Noise Formulas**

$$F_{no-filter} = F_1 + 4R_s \gamma_3 g_{do3} \left( \frac{\omega_0^2}{\omega_T^2} \right) \left( \frac{C_x^2}{g_{m3}^2} \omega_0^2 \right)$$

Overall NF of LNA/Filter is

$$F_{tot} = F_1 + \psi \cdot 4R_s (\gamma_5 g_{do5} + G_{L5}) \left( \frac{\omega_0^2}{\omega_T^2} \right)$$

Where 
$$\Psi = \frac{C_3^2 \cdot \omega_0^2}{\left(\frac{C_3^2}{C_x + C_3}\right)^2 \cdot \omega_0^2 + (G_{L5} - g_{m5})^2}$$
,
$$F_1 = 1 + \frac{1}{g_m^2 R_s} \cdot \begin{cases} \int \left[1 + s^2 C_{gs} \left(L_g + L_s\right) \left(1 + /c/\alpha \sqrt{\frac{\delta}{5\gamma}}\right)\right]^2 \\ -\left(s C_{gs} R_s\right)^2 \left(1 + /c/\alpha \sqrt{\frac{\delta}{5\gamma}}\right)^2 \\ -\frac{\alpha \delta}{5} \left(1 - /c/^2\right) g_m \left(s C_{gs}\right)^2 \left(R_s^2 - s L_g^2\right) \end{cases}$$

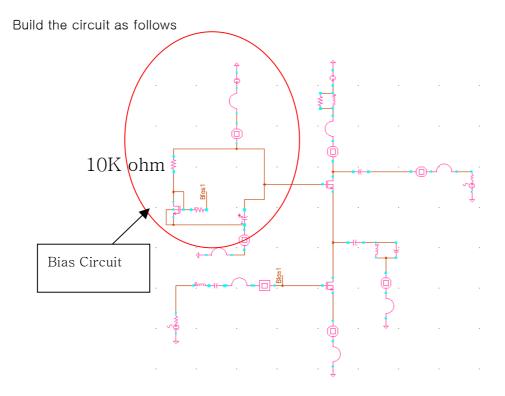
Note that the impedance of the filter at the frequency of the pole is high enough  $\rightarrow$   $F_{total} = F_1$ 

# 1.2 Circuit Implementation

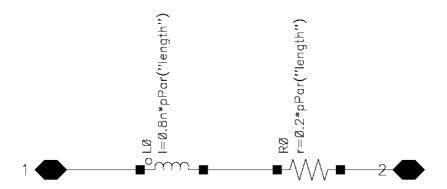
## 1.2.1 Setup Environment

Assume that we design the image rejection LNA operating at 5 GHz with the image signal equal to 5.5 Ghz  $\rightarrow$  Based on Eq. We can calculate the value of each component of the image rejection circuit as follows:

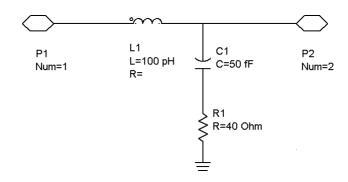
L1 (image rejection filter) = 2.2 nH, C1 (Image Rejection Filter) = 100f, C3 (Image Rejection Filter) = 300f



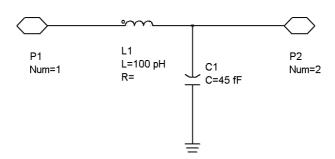
The model of bond-wire is shown in below



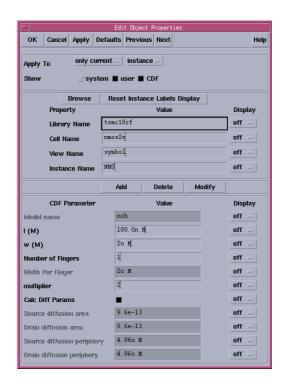
• The model of bond pad power is shown in below



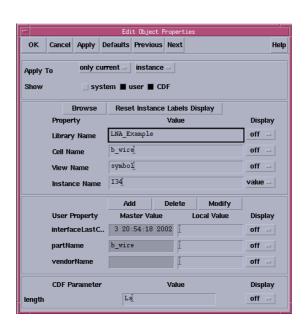
• The model of bond pad shield is shown in below



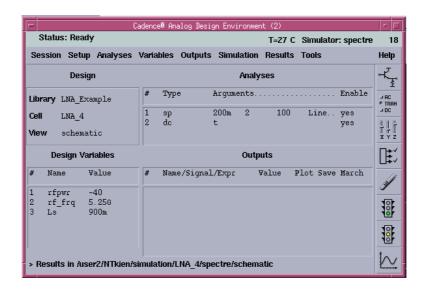
Size of bias transistor



The way to find the value of input and output matching are the same as the Low Noise Amplifier 1: Theory. However, the step to determine the value of Ls is different because now the degeneration inductor is made by bonding wire instead of using onchip inductor.



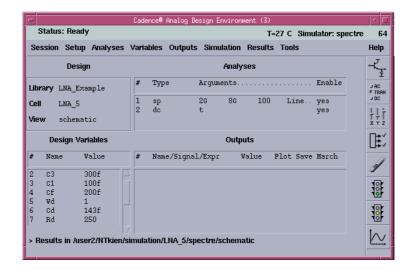
Sweep the value of Ls



Finally, we obtain the value of each component as follows

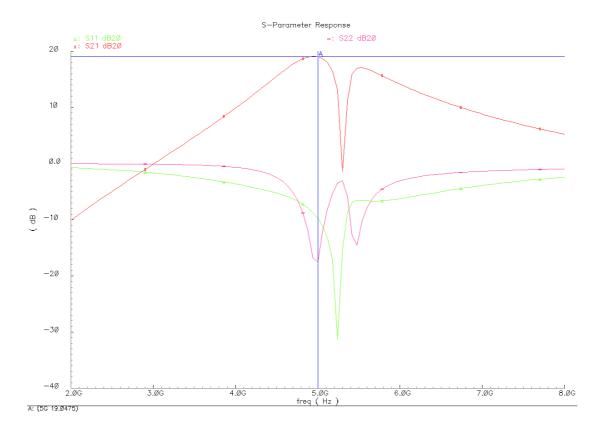
Ls = 0.3m, Lg = 2.5 nH, Ld (output inductance) = 2.3 nH, Rd (Output resistance) = 250 ohm
Cd (Ouput capacitance = 1443 fF

## 1.2.2 Run S-parameters simulation

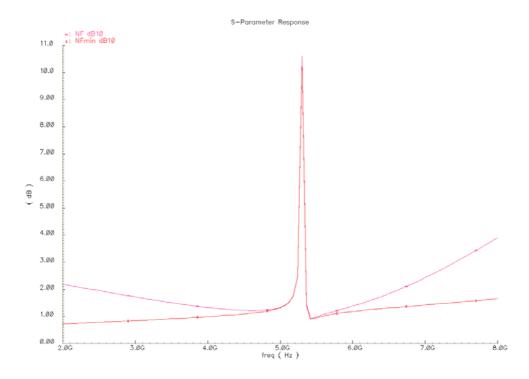


# 1.2.3 Plot Results

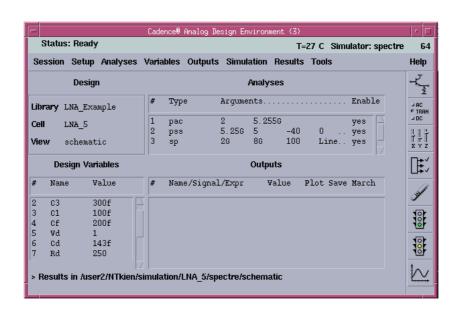
#### 1) S-Parameters



#### 2) NF and NFmin

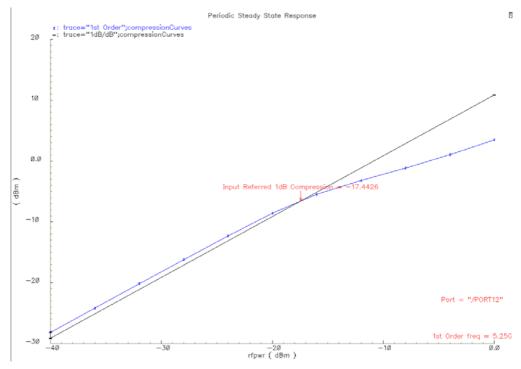


## 1.2.4. Check Linearity

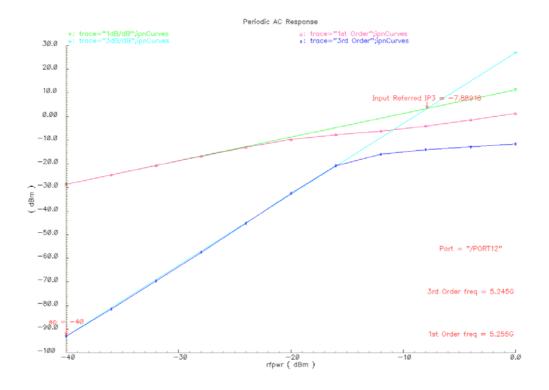


## 1.2.5. Plot Results

#### 1) 1dB compression point

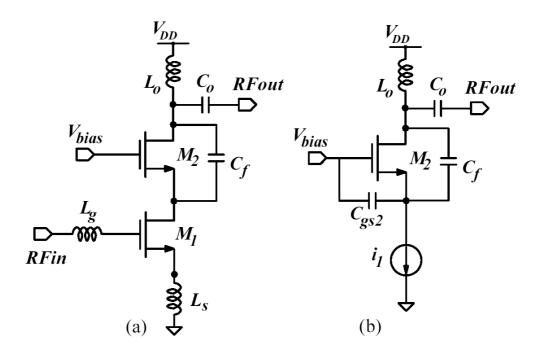


#### 2) IIP3



# 2. Gain Enhancement Technique Using Positive Feedback

## 2.2.1 Circuit Descriptions



- ightharpoonup The positive feedback is realized by  $C_f$
- This phenomenon can be understood by another point of view as the form of oscillator.  $C_{gs1}$ ,  $C_f$ , and  $M_1$  constitute an oscillator topology with inductive termination at the output.
- > The gain of amplifier without C<sub>f</sub> is given by

$$A_{v} = g_{m1}Q_{in}\frac{1}{G_{tot}} = G_{eff}\frac{1}{G_{tot}}$$
 (5.1)

- g<sub>m</sub> is the transconductance of M<sub>1</sub>,
- Q<sub>in</sub> is the quality factor of the input circuit
- Geff is the effective transconductance of the amplifier
- $G_{tot}$  is the total transconductance at the drain of  $M_2$  and is dominated by the equivalent parallel conductance of the inductor  $(G_P)$ .

$$G_P = \frac{1}{Q_L^2 R_{L_0}}$$
 (5.2)

- $\bullet\ \ R_{Lo}$  is the series resistance of the inductor
- ightharpoonup Low  $Q_L$  lead to high  $G_P$  ightharpoonup high  $G_{tot}$  ightharpoonup Limit the  $A_V$  of the amplifier
- From (5.1) → Gain of amplifier can be improved by larger G<sub>eff</sub> or larger L<sub>o</sub> → larger power consumption or an impracticably larger value for the inductor
- > The Q of the amplifier without C<sub>f</sub> is given by

$$Q = \frac{1}{G_{tot}} \sqrt{\frac{C_{tot}}{L_o}}$$
 (5.3)

- C<sub>tot</sub> is the total capacitance at the drain of M<sub>2</sub>.
- From (5.2) and (5.3): Low Q<sub>L</sub> will also limit the Q of amplifier
- Assume that  $\omega << g_{m2}/\left(C_{gs2}+C_f\right)$ , from Fig.-b, the negative conductance (G<sub>N</sub>) is generated by C<sub>f</sub> is

$$G_{N} = \frac{\omega^{2} C_{gs2} \left( C_{N} + C_{gd2} \right)}{g_{m2}}$$
 (5.4)

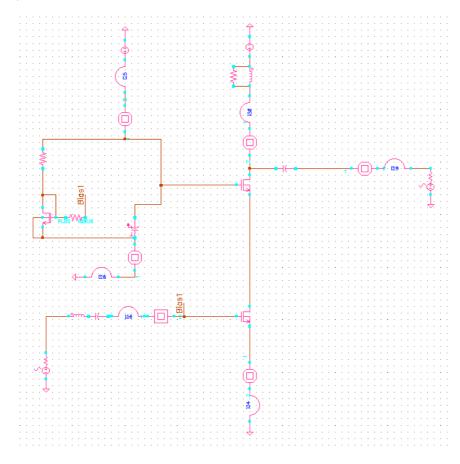
> The total conductance now is given by

$$G_{tot} = G_P - G_N \tag{5.5}$$

- From (5.5) by using  $C_f$ , the total conductance is reduced  $\rightarrow$  improve gain of LNA
- Note that no additional active is used therefore no more DC power dissipated and no noise contributed.
- ightharpoonup The limit to amount of feedback is governed by stability consideration. To ensure the stability condition,  $G_{tol}$  must always positive.

# 2.2.2 Ciruit Implementation

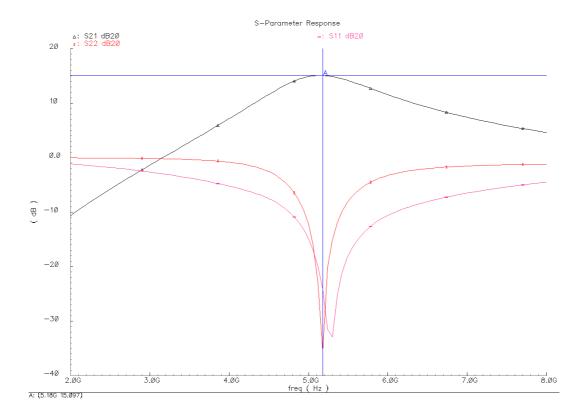
# 2.2.1 Setup Environment

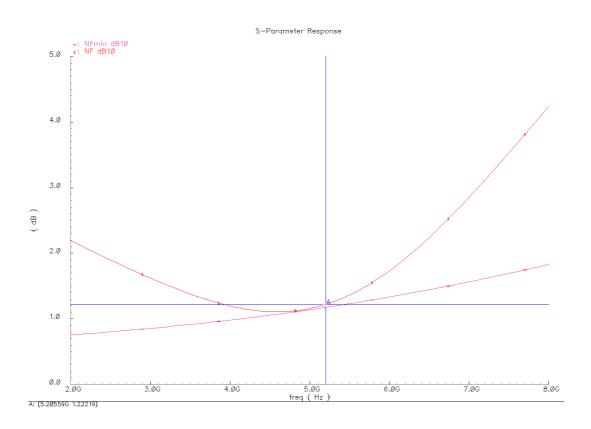


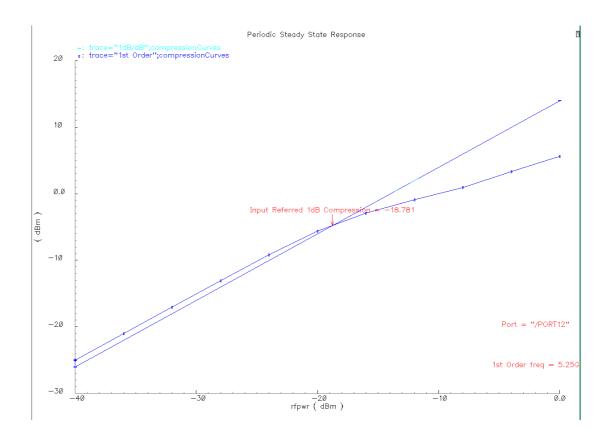
The value of component of matching network: Ls = 530 mm, Lg = 2.6 nH

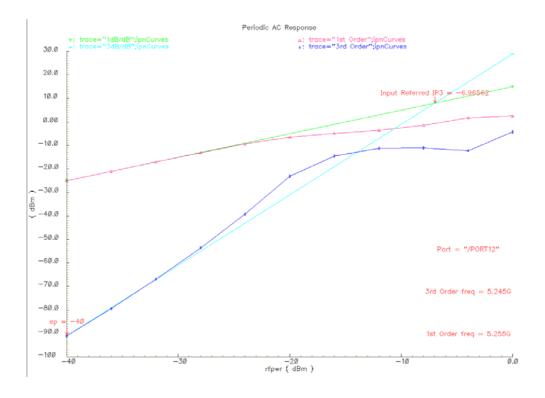
The value of output matching network: L1, R1 va C1 are:

# 2.2.2 Runsimulation



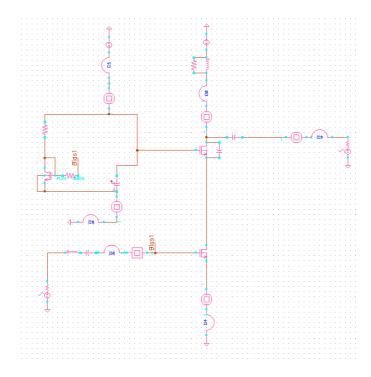




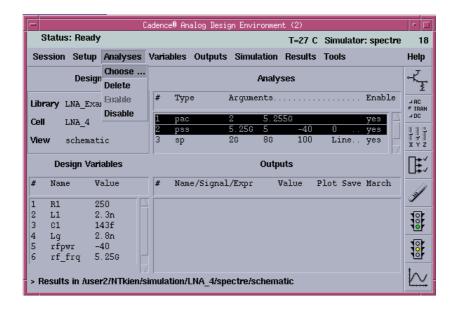


Insert additional capacitor connected to drain and source terminal of the cascode transistor

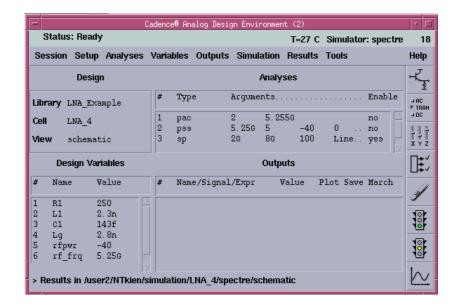
Highline this capacitor and as set its capacitance as variable C<sub>f</sub>



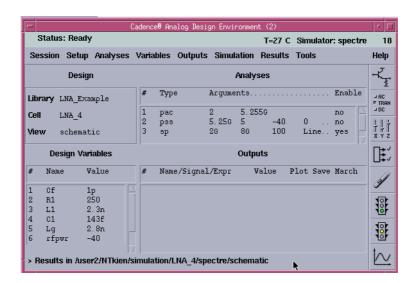
On the Anallog Design Inviroment windown, invisible PSS and PAC analyses by doing as follows



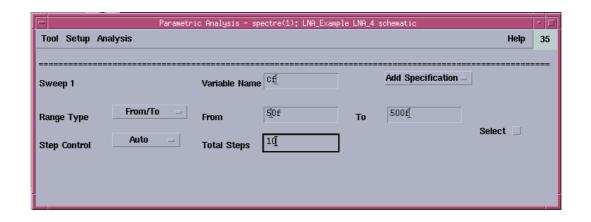
> Anallog Design Inviroment windown becomes



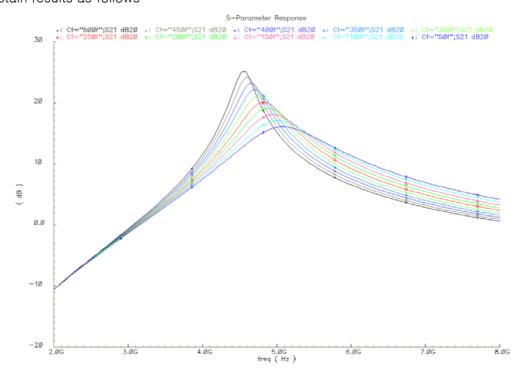
Click Variable → Copy from cell view



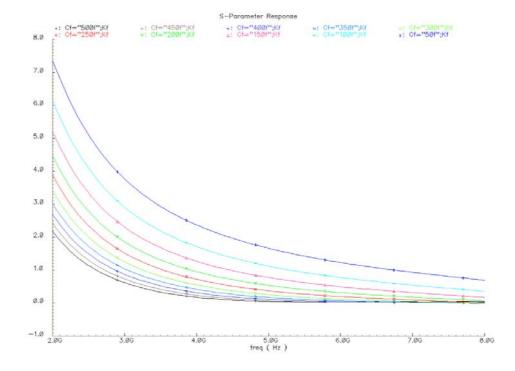
Click tool the Parametric Analysis windown will appear. After that we modify it as follows



Click Analysis  $\rightarrow$  Start in order to run the simulation. After simulation, Plot S21, and K-factor we can obtain results as follows



K factor



Considering the value of K factor  $\rightarrow$  choose value of  $C_f$ .